

(10) **Patent No.:** US 9,219,164 B2
(45) **Date of Patent:** Dec. 22, 2015

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(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 0 days.

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(21) Appl. No.: 13/860,690

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(22) Filed: **Apr. 11, 2013**

Ohara, H et al., "Amorphous In—Ga—Zn—Oxide TFTs with Suppressed Variation for 4.0 inch QVGA AMOLED Display,"AM-FPD '09 Digest of Technical Papers, Jul. 1, 2009, pp. 227-230, The Japan Society of Applied Physics.

(65) **Prior Publication Data**

(Continued)

US 2013/0277676 A1 Oct. 24, 2013

(30) **Foreign Application Priority Data**

Primary Examiner — Ajay K Arora

Apr. 20, 2012 (JP) 2012-096952
May 24, 2012 (JP) 2012-118815

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(57) **ABSTRACT**

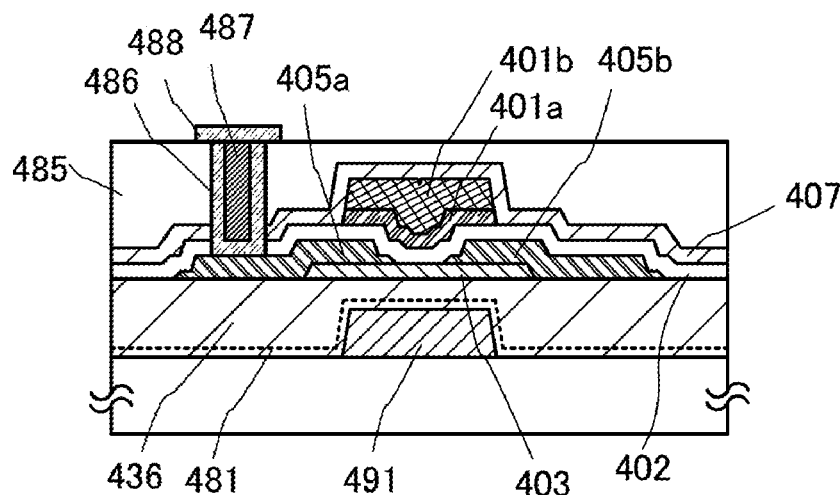
(51) **Int. Cl.**
H01L 29/10 (2006.01)
H01L 29/786 (2006.01)
H01L 29/417 (2006.01)

(52) **U.S. Cl.**
CPC *H01L 29/78693* (2013.01); *H01L 29/41733*
(2013.01); *H01L 29/7869* (2013.01)

(58) **Field of Classification Search**
CPC H01L 29/786; H01L 29/41733; H01L 29/7869
USPC 257/43
See application file for complete search history.

To give stable electrical characteristics to and improve reliability of a semiconductor device including a transistor in which an oxide semiconductor film is used for a channel formation region. As a base film, an insulating film or an oxide semiconductor film is used. A single-layer metal film is formed over the base film. After that, a resist mask is formed, and etching is performed plural times. Accordingly, electrodes each including projecting portions when seen in cross-section are formed. Even when a gate insulating film over the source electrode layer and the drain electrode layer or an oxide semiconductor film has a small thickness, disconnection of the gate insulating film is unlikely to occur.

15 Claims, 16 Drawing Sheets



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* cited by examiner

FIG. 1A

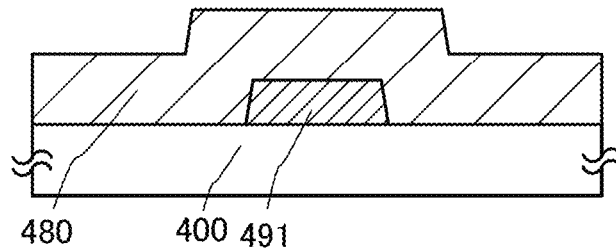


FIG. 1B

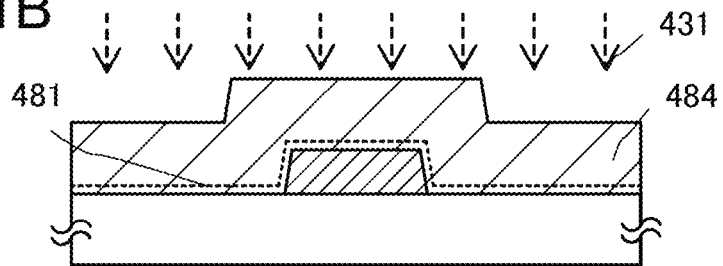


FIG. 1C

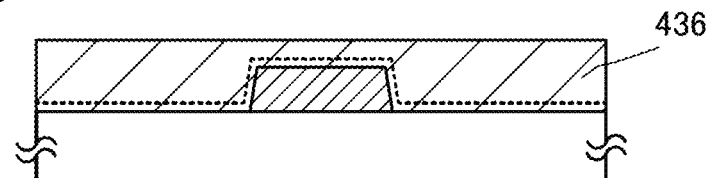


FIG. 1D

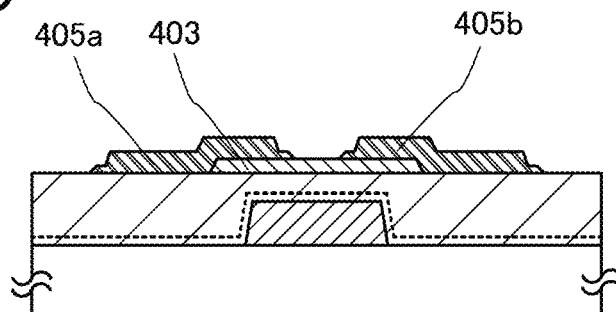


FIG. 2A

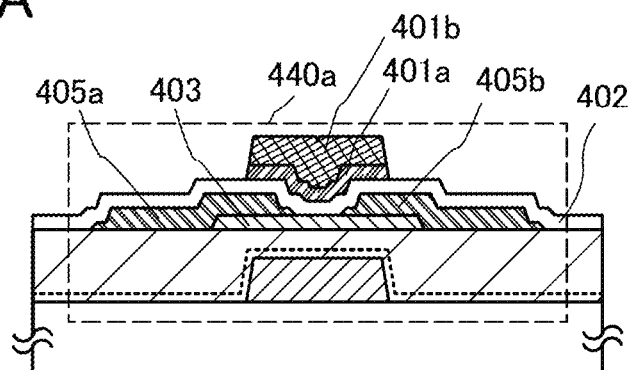


FIG. 2B

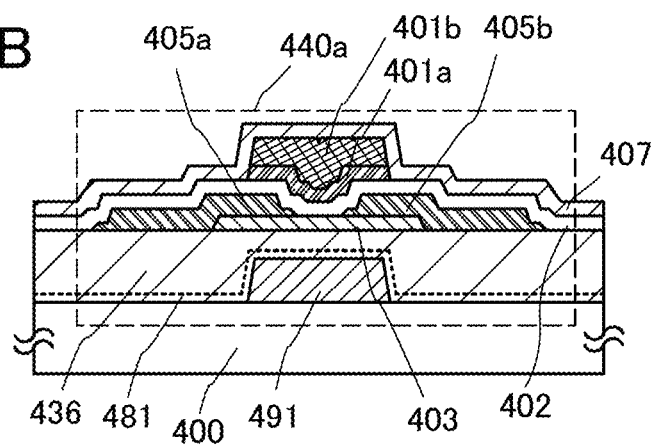


FIG. 2C

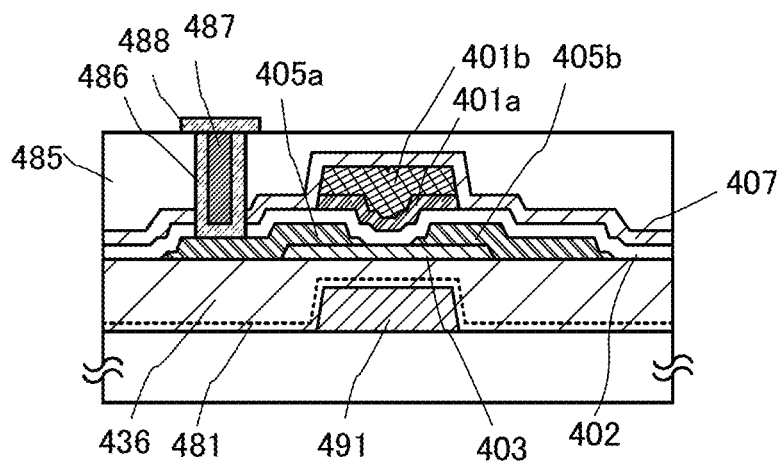


FIG. 3A

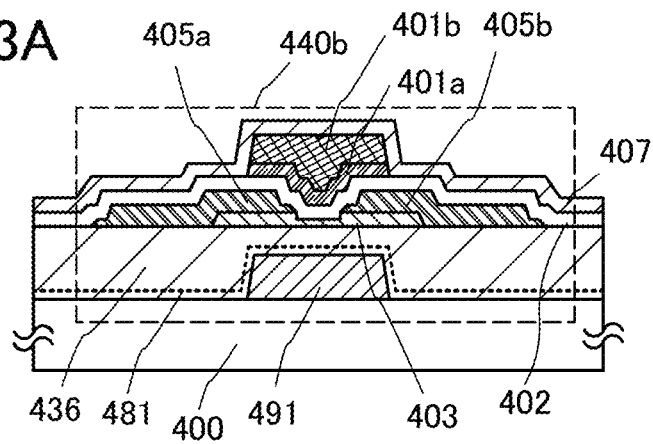


FIG. 3B

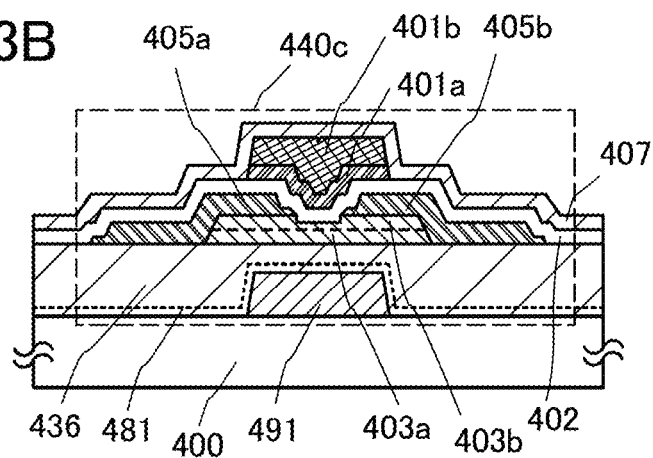


FIG. 3C

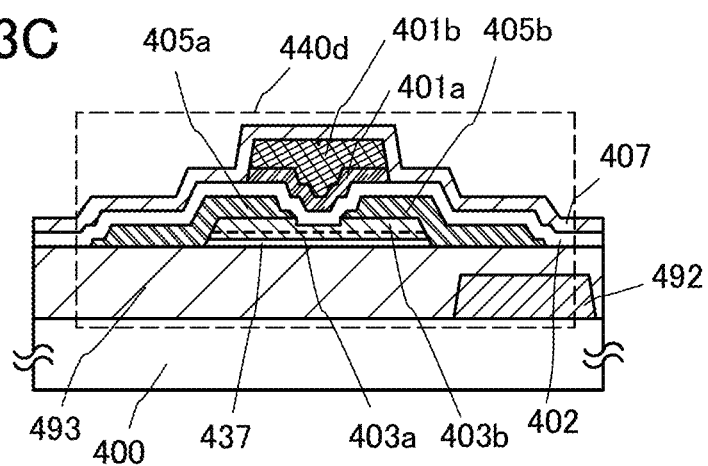


FIG. 4A

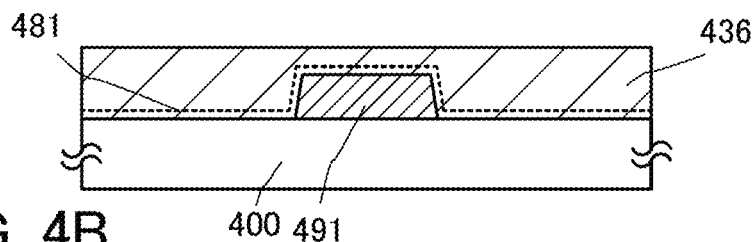


FIG. 4B

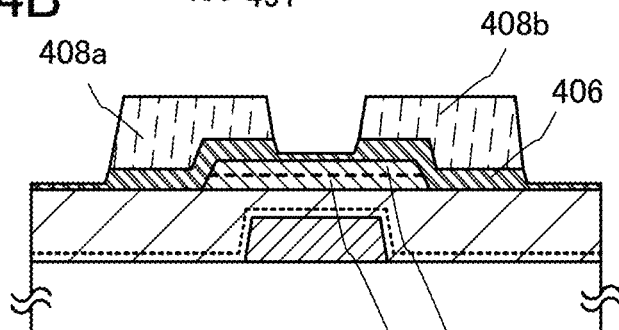


FIG. 4C

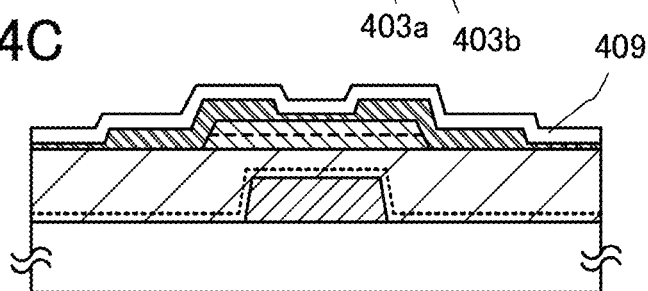


FIG. 4D

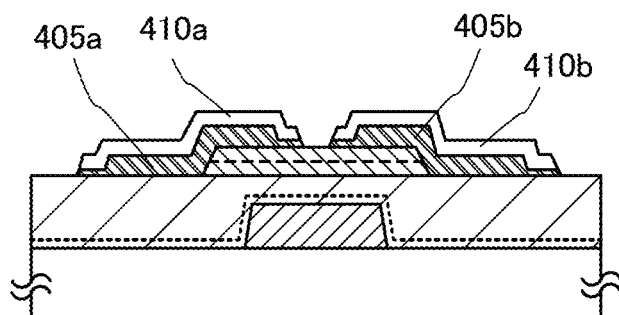


FIG. 4E

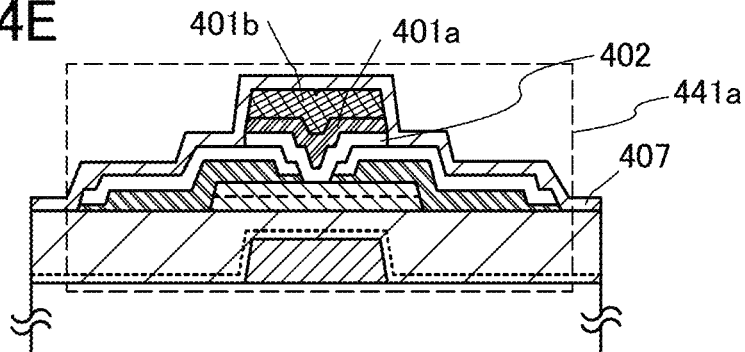


FIG. 5A

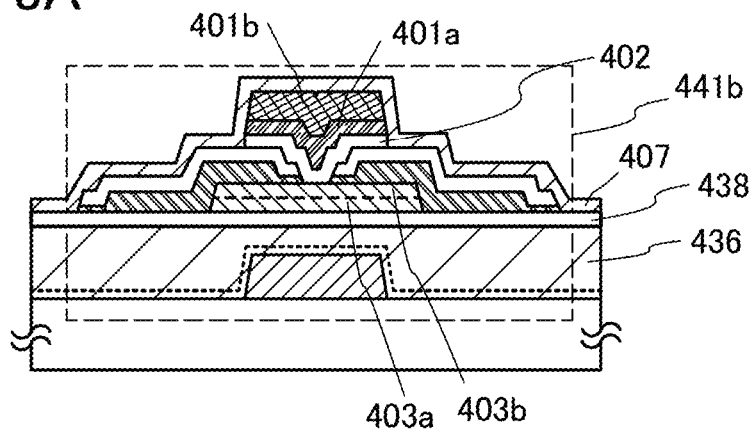


FIG. 5B

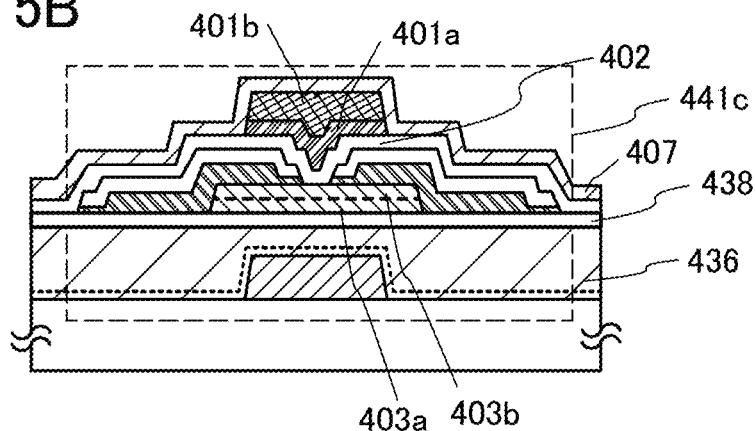


FIG. 5C

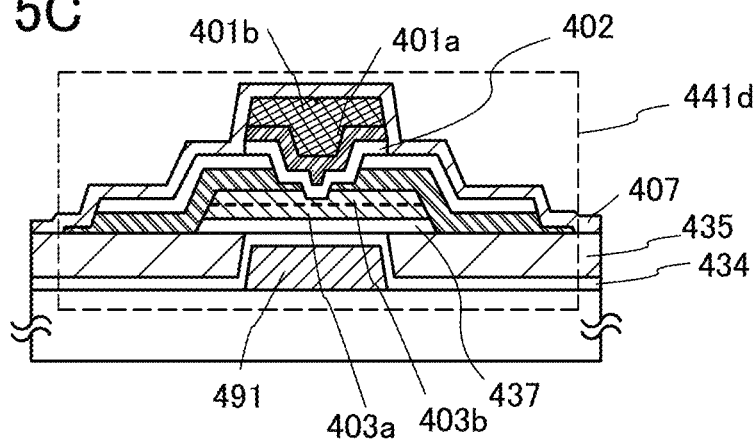


FIG. 6A

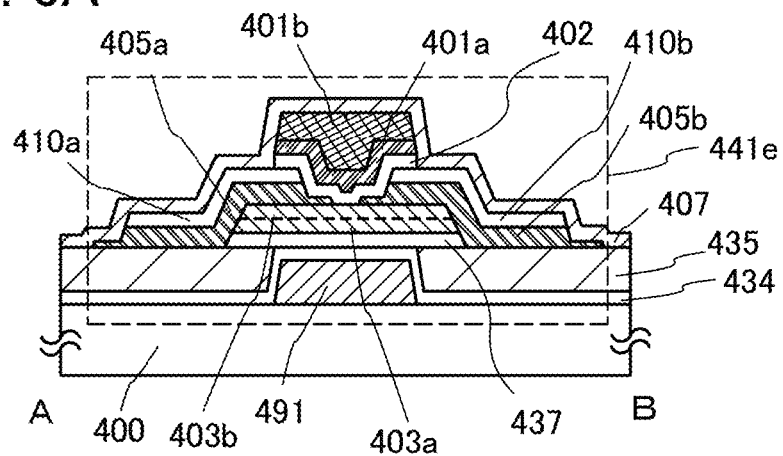


FIG. 6B

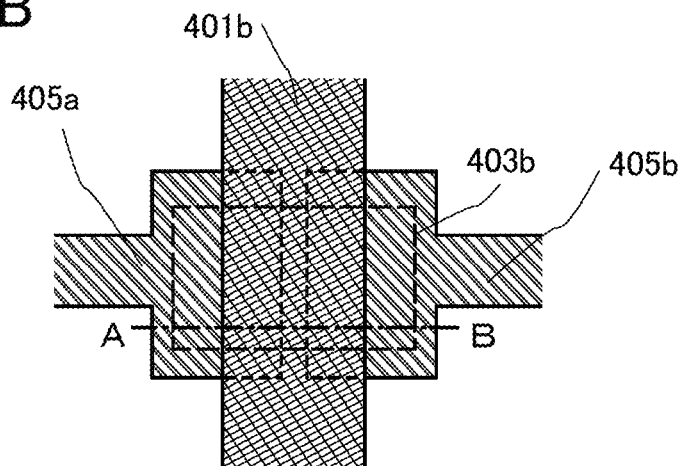


FIG. 7A

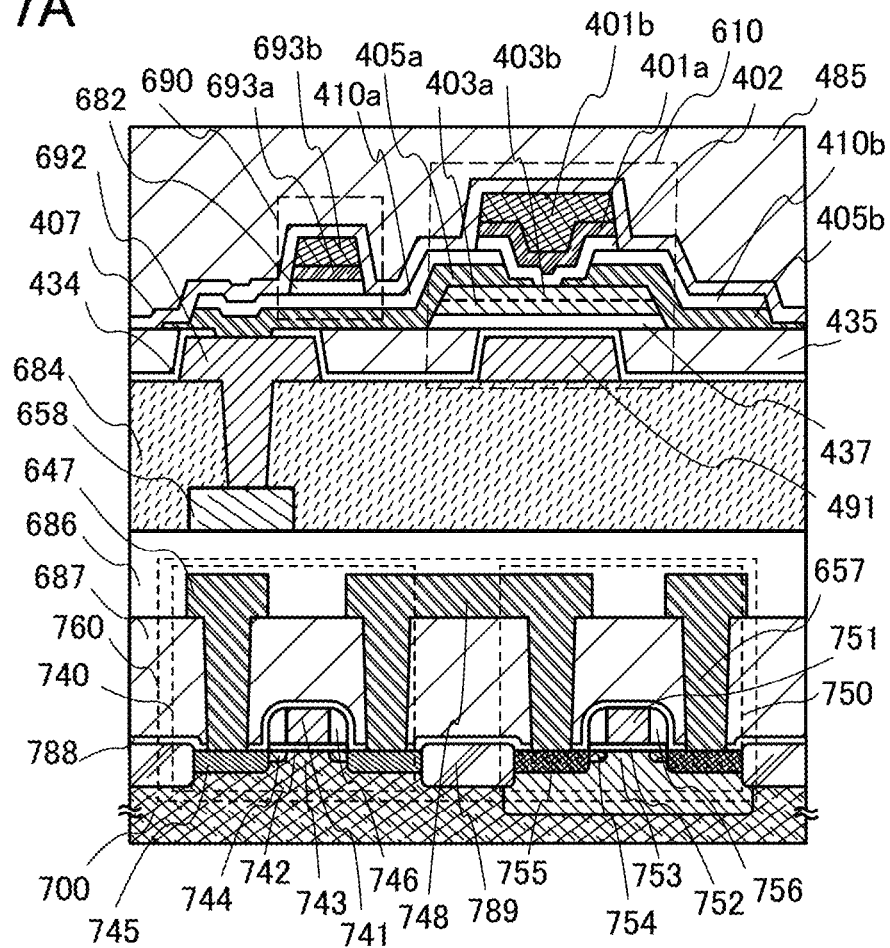


FIG. 7B

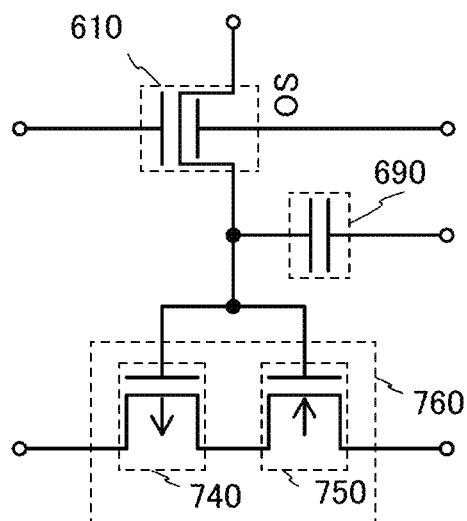


FIG. 8A

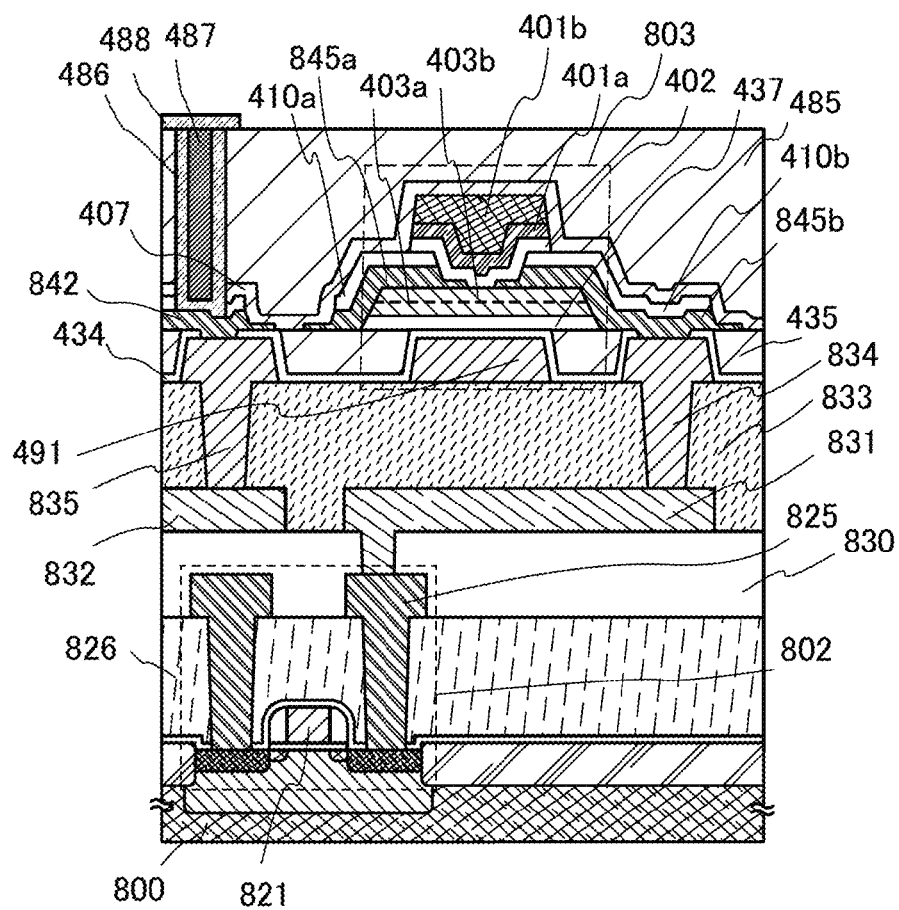


FIG. 8B

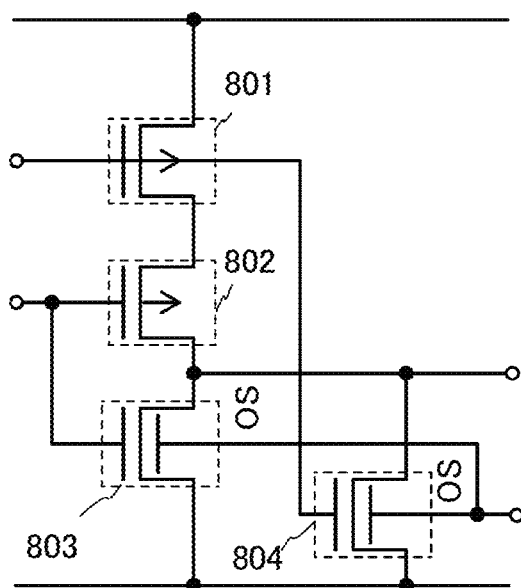


FIG. 8C

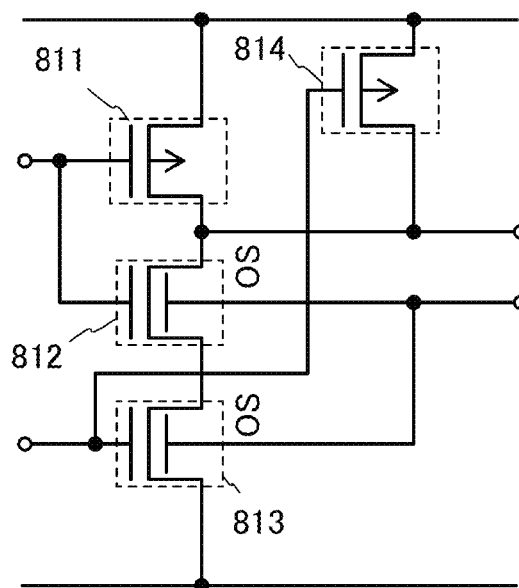


FIG. 9

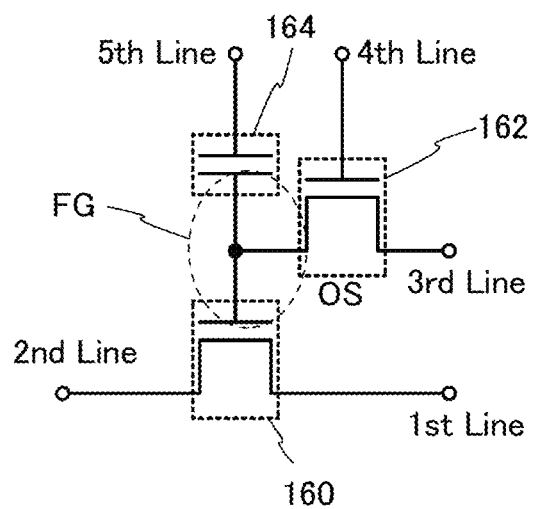


FIG. 10

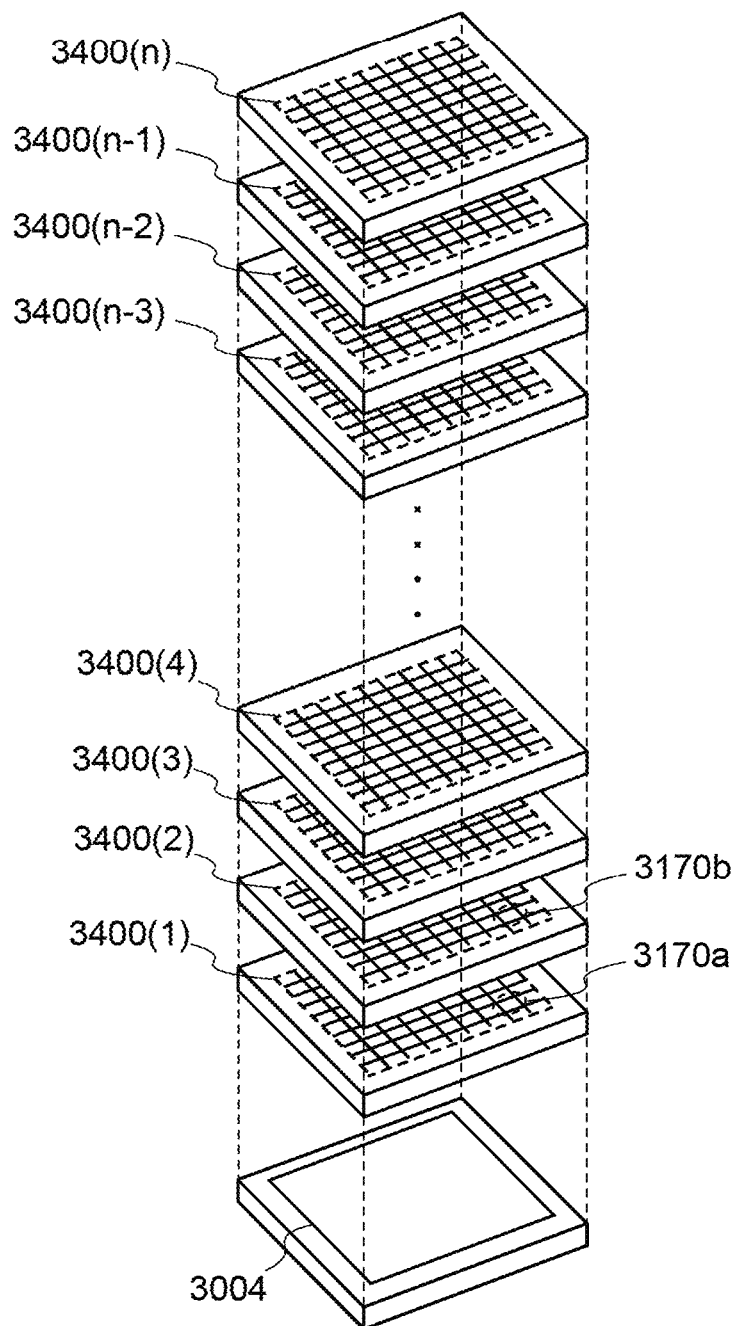


FIG. 11A

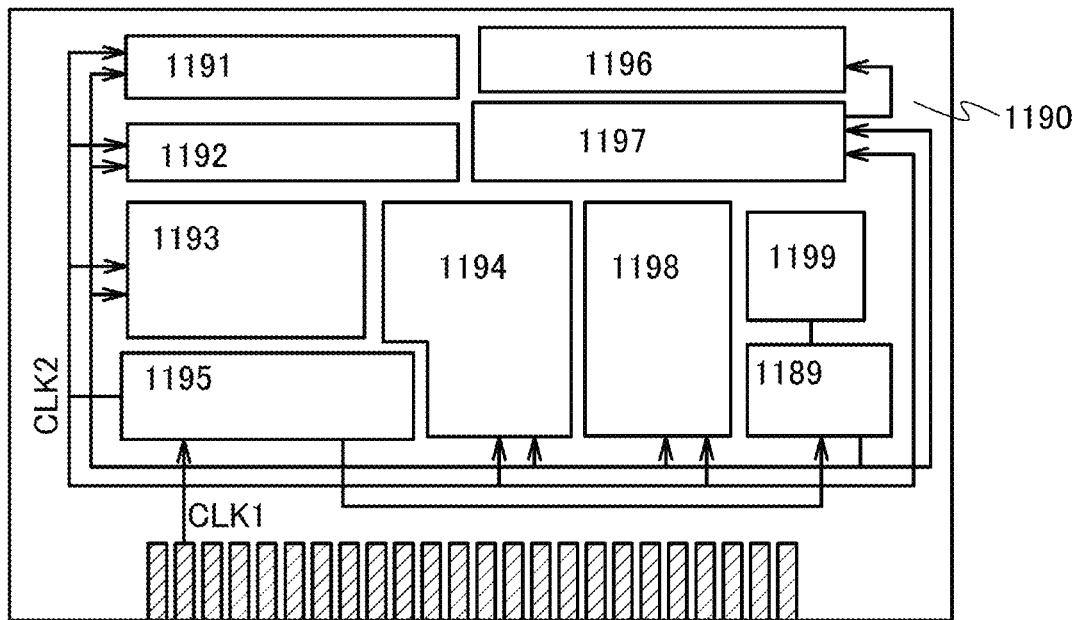


FIG. 11B

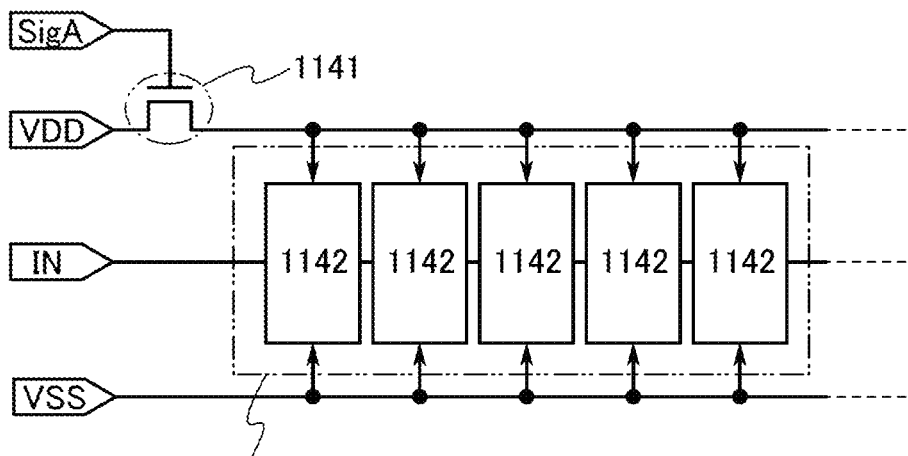


FIG. 11C

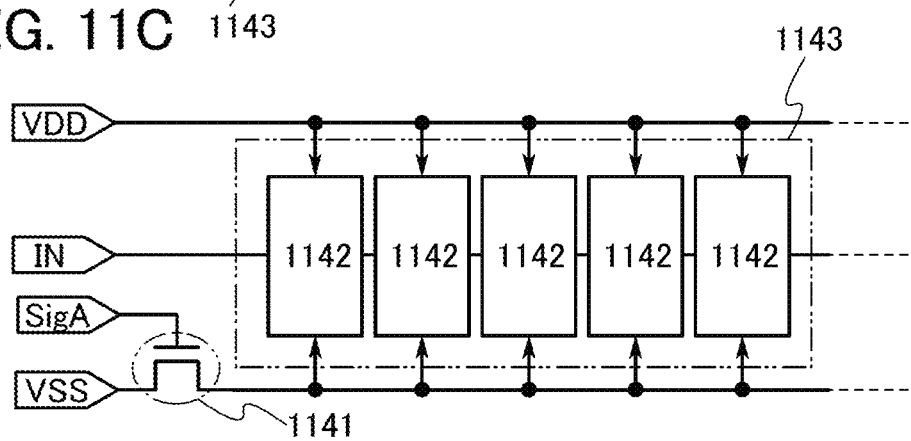


FIG. 12A

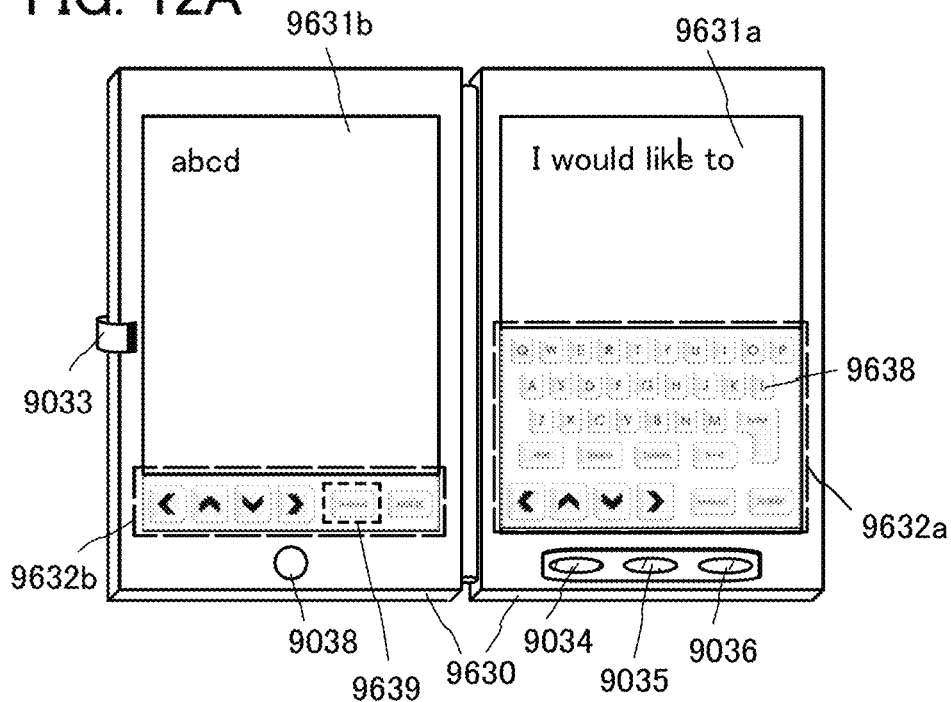


FIG. 12B

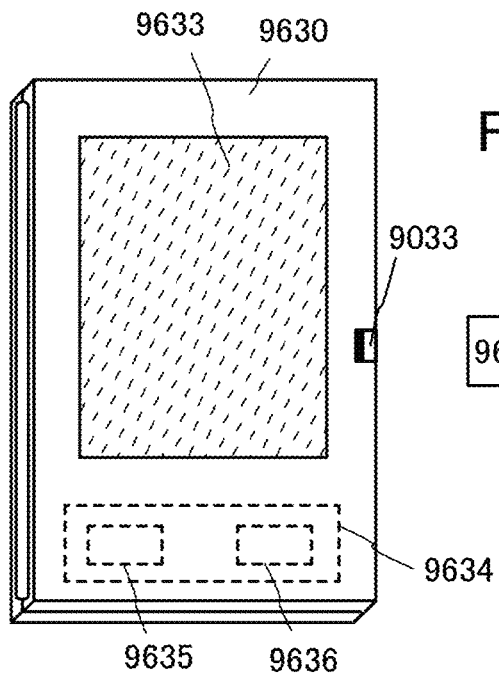


FIG. 12C

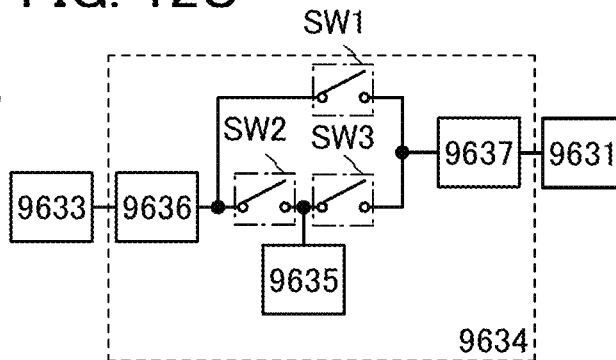


FIG. 13A

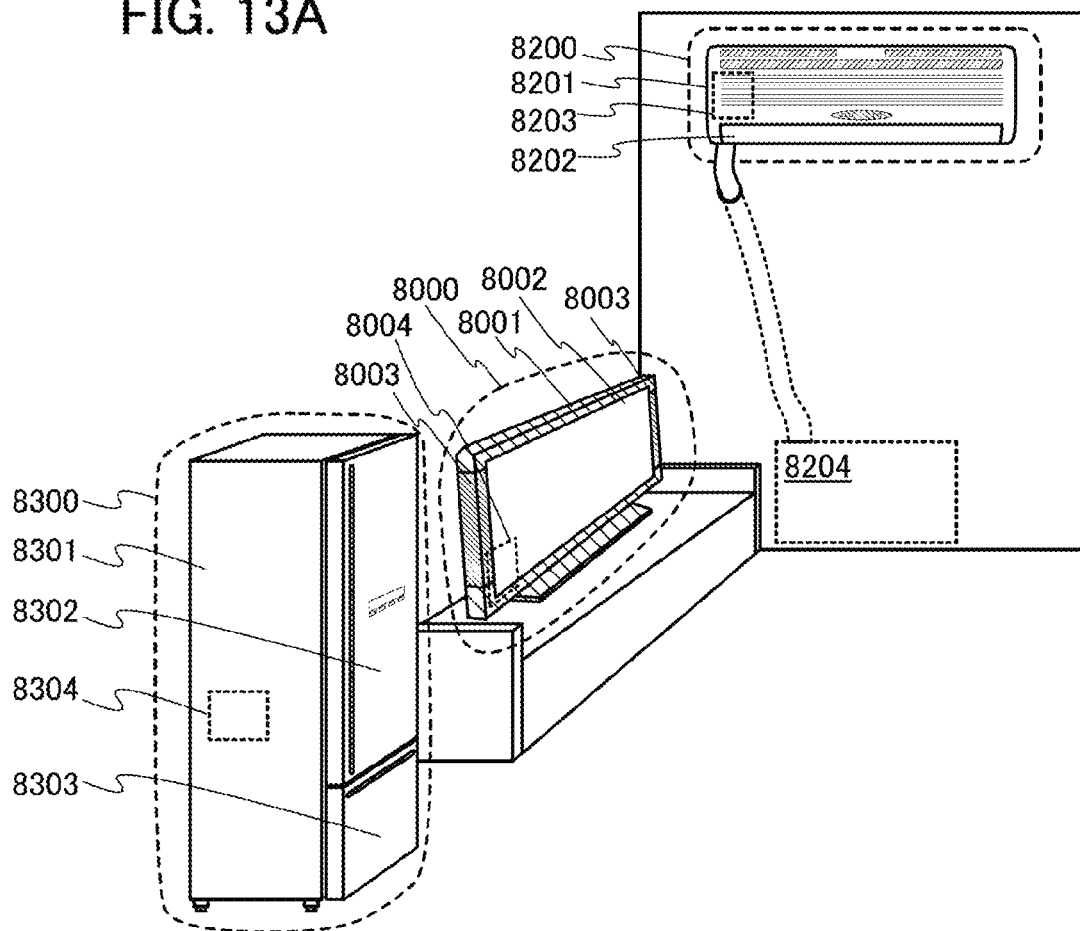


FIG. 13B

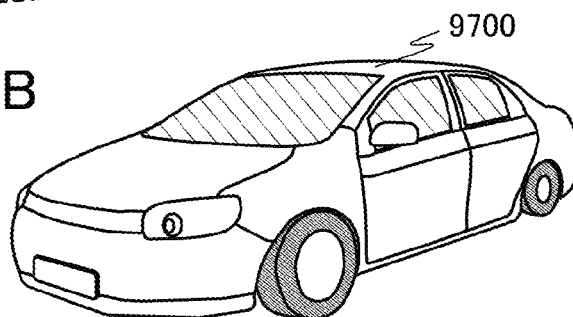


FIG. 13C

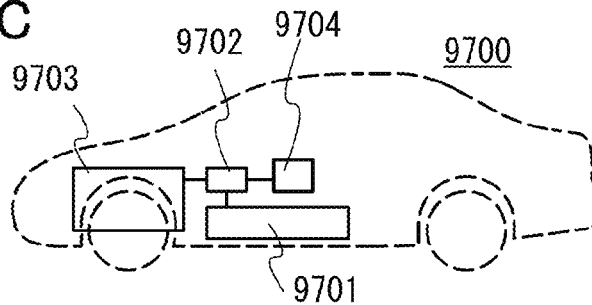


FIG. 14

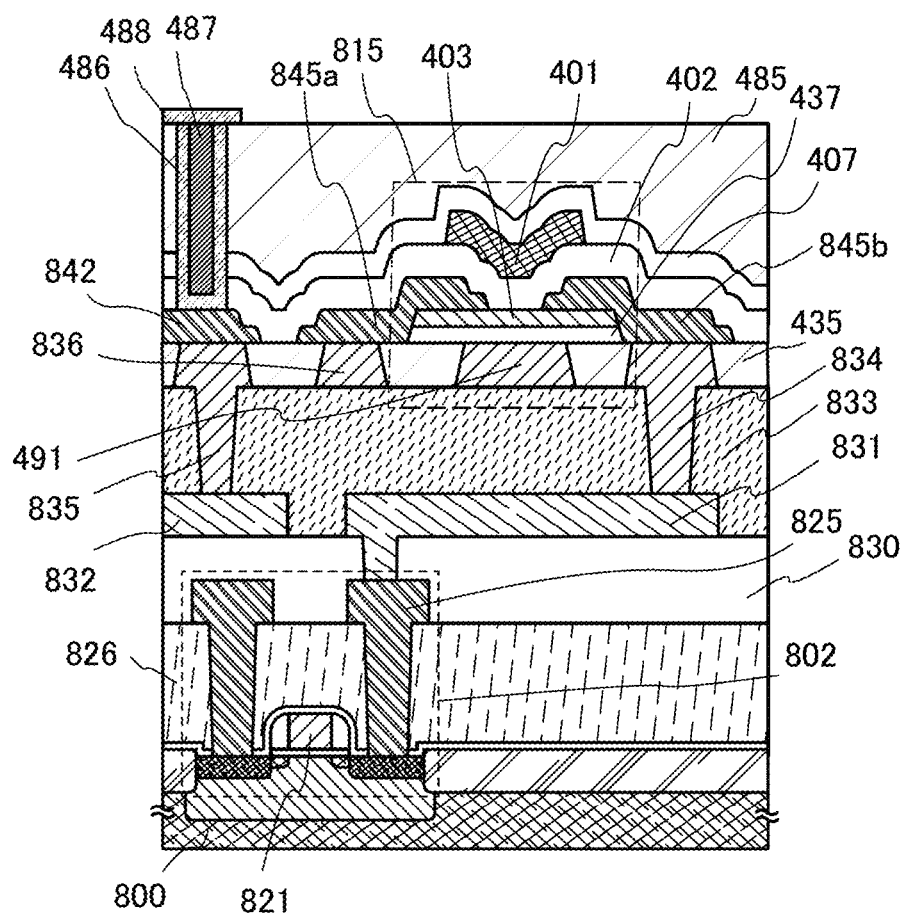


FIG. 15A

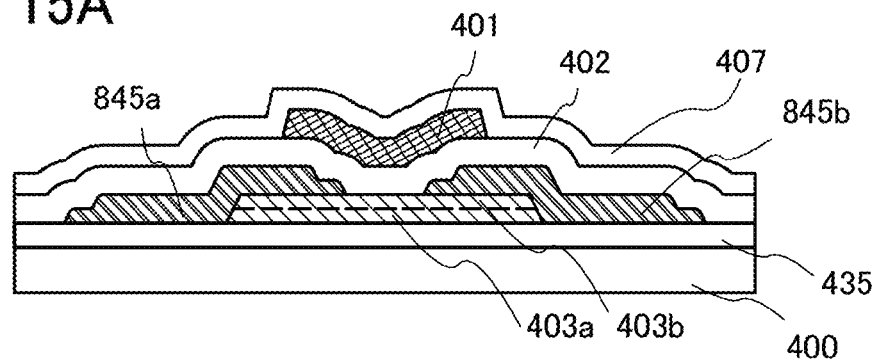


FIG. 15B

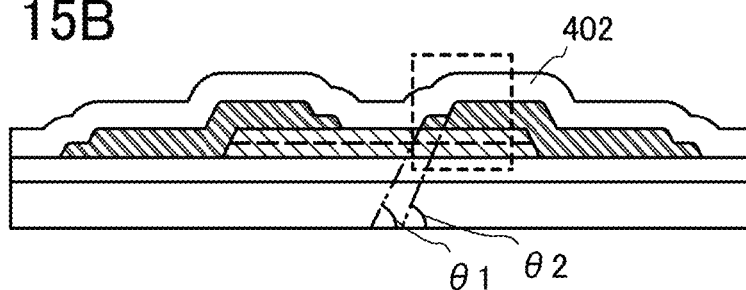


FIG. 15C

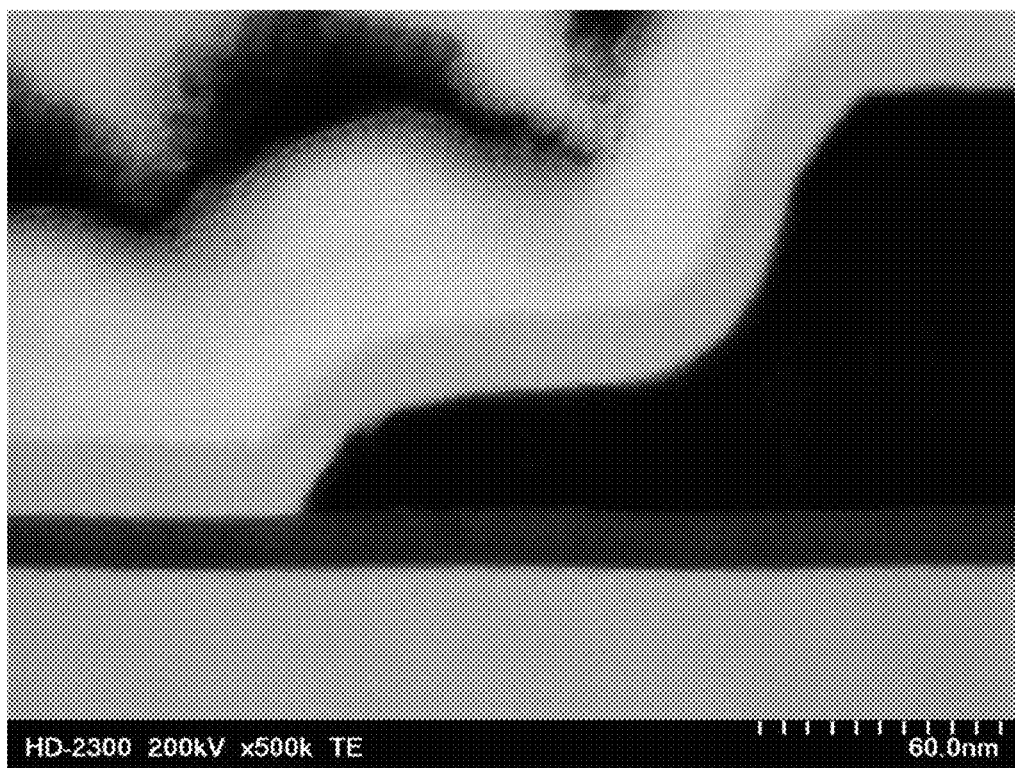


FIG. 16A

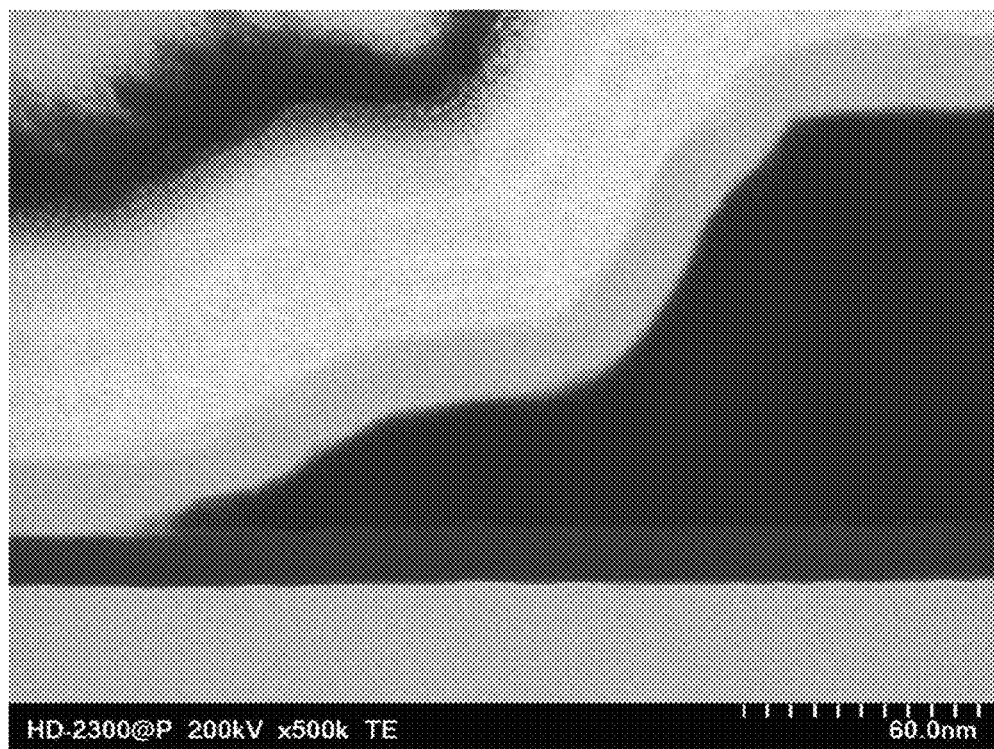
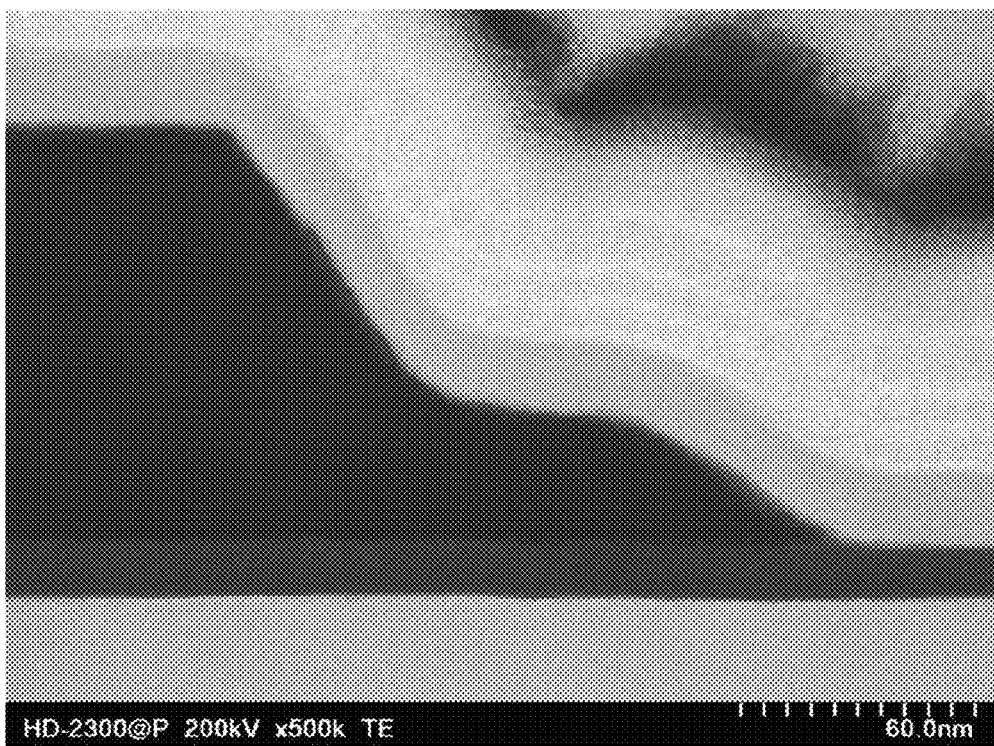


FIG. 16B



1

SEMICONDUCTOR DEVICE WITH OXIDE SEMICONDUCTOR CHANNEL

BACKGROUND OF THE INVENTION

1. Field of the Invention

The present invention relates to a semiconductor device including an oxide semiconductor and a manufacturing method thereof.

In this specification, a semiconductor device generally means a device which can function by utilizing semiconductor characteristics, and an electrooptic device, a semiconductor circuit, and an electronic device are all semiconductor devices.

2. Description of the Related Art

A technique for manufacturing a transistor or the like by using an oxide semiconductor film for a channel formation region and applying it to a display device has been attracting attention. Examples of such a transistor include a transistor in which zinc oxide (ZnO) is used as an oxide semiconductor film and a transistor in which $\text{InGaO}_3(\text{ZnO})_m$ is used as an oxide semiconductor film. A technique for manufacturing such a transistor including an oxide semiconductor film over a light-transmitting substrate and applying it to a switching element or the like of an image display device is disclosed in Patent Documents 1 and 2.

Patent document 3 discloses a structure of a transistor including a source electrode and a drain electrode in contact with an oxide semiconductor layer, a gate electrode overlapping with the oxide semiconductor layer, and a gate insulating film provided between the oxide semiconductor layer and the gate electrode, in which the source electrode and the drain electrode each include a first conductive layer, and a second conductive layer having a region which extends in a channel length direction from an end portion of the first conductive layer.

In Patent Document 4, a structure in which gate electrodes are formed below and over an oxide semiconductor layer is disclosed.

REFERENCE

Patent Document

- [Patent Document 1] Japanese Published Patent Application No. 2007-123861
- [Patent Document 2] Japanese Published Patent Application No. 2007-096055
- [Patent Document 3] Japanese Published Patent Application No. 2007-171721
- [Patent Document 4] Japanese Published Patent Application No. 2011-103458

SUMMARY OF THE INVENTION

One object of the present invention is to provide a structure of a transistor in which a source electrode layer and a drain electrode layer are formed using a single-layer metal film over an oxide semiconductor film and electric-field concentration which might occur in end portions of the source electrode layer and the drain electrode layer is reduced.

Another object of the present invention is to give stable electrical characteristics to a semiconductor device including a transistor in which an oxide semiconductor film is used for a channel formation region and to improve reliability of the semiconductor device.

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Another object of the present invention is to form a source electrode layer and a drain electrode layer each having a cross-sectional shape with which disconnection of a gate insulating film is unlikely to occur even when the gate insulating film over the source electrode layer and the drain electrode layer or an oxide semiconductor film has a small thickness.

As a base film, an insulating film or an oxide semiconductor film is used. A single-layer metal film is formed over the base film. After that, a resist mask is formed, and etching is performed plural times. Accordingly, electrodes each including projecting portions when seen in cross-section are formed.

Specifically, a resist mask is formed over a metal film, first etching for removing the metal film to approximately half the thickness so that the metal film partly has a small thickness is performed, and ashing is performed on the resist mask for reducing the area of the resist mask. After that, second etching is performed with the resist mask, which is reduced in size, so that single-layer metal films each including projecting portions are formed.

In the case where an oxide semiconductor film is used as the base film, when or after a single-layer metal film in contact with the oxide semiconductor film is processed, etching may be performed with the use of the metal film as a mask so as to form a thin-film region of the oxide semiconductor film (that is, a region which has a smaller thickness than a region overlapping with the metal film and does not overlap with the metal film). In such a case, a transistor in which the thin-film region serves as a channel formation region can be manufactured.

In the case where a source electrode layer and a drain electrode layer are formed over the oxide semiconductor film, the source electrode layer and the drain electrode layer each including projecting portions extending in the channel length direction can be formed by the above steps. In the case where a gate insulating film is formed over the source electrode layer and the drain electrode layer each having such a cross-sectional shape, disconnection of the gate insulating film is unlikely to occur even when the gate insulating film or the oxide semiconductor film has a small thickness. By forming the source electrode layer and the drain electrode layer each including the projecting portions extending in the channel length direction using a single-layer metal film, the manufacturing process can be simple as compared to a case of using stacked metal films.

Some of the projecting portions of the source electrode layer and the drain electrode layer overlap with the oxide semiconductor film; thus, electric-field concentration is reduced, which contributes to improvement in electrical characteristics and reliability of a transistor.

By providing gate electrode layers below and over an oxide semiconductor film and setting the potential of one of the gate electrode layers to GND, the threshold voltage of the transistor is increased, so that a normally-off transistor can be provided.

In addition, the gate electrode layer having a potential of GND has a function of blocking an external electric field, that is, a function of preventing an external electric field (particularly, a function of preventing static electricity) from affecting a transistor. A blocking function of the gate electrode layer having a potential of GND can prevent variation in electrical characteristics of the transistor due to the effect of an external electric field such as static electricity.

One embodiment of the invention disclosed in this specification is a semiconductor device including a conductive layer; an oxide insulating film over the conductive layer; an

oxide semiconductor film which is over the oxide insulating film and includes a channel formation region; a source electrode layer and a drain electrode layer which are over the oxide semiconductor film and are electrically connected to the oxide semiconductor film; a gate insulating film over the oxide semiconductor film, the source electrode layer, and the drain electrode layer; and a gate electrode layer which is over the gate insulating film and overlaps with the channel formation region. The source electrode layer and the drain electrode layer are formed using a single-layer metal film and each include projecting portions extending in the channel length direction. Some of the projecting portions which overlap with the oxide semiconductor film overlap with the conductive layer.

The above structure, which includes the source electrode layer and the drain electrode layer each including the projecting portions extending in the channel length direction, contributes to reduction in electric-field concentration and improvement in electrical characteristics and reliability of a transistor.

Since the source electrode layer and the drain electrode layer each including the projecting portions extending in the channel length direction are included, disconnection of the gate insulating film is unlikely to occur even when the gate insulating film provided over the source electrode layer and the drain electrode layer or the oxide semiconductor film has a small thickness. By forming the source electrode layer and the drain electrode layer each including the projecting portions extending in the channel length direction using a single-layer metal film, the process can be simple.

In the above structure, the conductive layer is provided so as to be embedded in the oxide insulating film. In the oxide insulating film, an oxygen-excess region which contains oxygen whose proportion is higher than that in the stoichiometric composition of the oxide semiconductor film exists in the vicinity of the bottom surface of the oxide insulating film and the vicinity of the conductive layer in a region where the conductive layer exists.

The oxygen-excess region can be formed by forming a conductive layer, forming an oxide insulating film over the conductive layer, and then performing oxygen adding treatment (oxygen doping treatment) on the oxide insulating film having the top surface including a projecting portion reflecting the shape of the conductive layer. After forming the oxygen-excess region, planarization treatment is performed on the oxide insulating film in order to remove the projecting portion of the top surface. For the planarization treatment, a chemical mechanical polishing method is used.

By the planarization treatment, the oxide insulating film over the conductive layer is selectively removed to be thin, whereby the distance between the oxygen-excess region over the conductive layer and the top surface of the oxide insulating film becomes shorter. In contrast, a region of the oxide insulating film in which the conductive layer does not exist is hardly removed, and the oxygen-excess region exists in the vicinity of the bottom surface of the oxide insulating film. Thus, in the oxide insulating film, the oxygen-excess region is provided at a shallow position from the top surface of the oxide insulating film in the region where the conductive layer exists and is provided at a deep position from the top surface of the oxide insulating film in another region (i.e., the region where the conductive layer does not exist).

Since the oxygen-excess region can be provided close to the oxide semiconductor film in a part of the oxide insulating film over which the oxide semiconductor film (at least the channel formation region) is provided and which overlaps with the conductive layer, oxygen can be efficiently supplied

from the oxygen-excess region to the oxide semiconductor film. Supply of oxygen can be promoted by heat treatment.

Thus, in the semiconductor device, oxygen vacancies in the oxide semiconductor film and at the interface between the oxide insulating film and the oxide semiconductor film can be compensated efficiently.

As the oxide semiconductor film including the channel formation region, stacked oxide semiconductor films having different compositions can be used. For example, stacked films in which an In—Ga—Zn-based oxide film formed with a target having an atomic ratio of In:Ga:Zn=3:1:2 (=1/2:1/6:1/3) and an In—Ga—Zn-based oxide film formed with a target having an atomic ratio of In:Ga:Zn=1:1:1 (=1/3:1/3:1/3) are stacked in this order are used. In this case, a film in contact with the gate insulating film is preferably the In—Ga—Zn-based oxide film formed with the target having an atomic ratio of In:Ga:Zn=1:1:1.

By performing etching when or after the source electrode layer and the drain electrode layer each including the projecting portions extending in the channel length direction are formed, a depressed portion may be formed in the oxide semiconductor film including the channel formation region. Forming a depressed portion in the oxide semiconductor film leads to reduction in electric-field concentration and can suppress degradation of switching characteristics. In the case where the stacked oxide semiconductor films having different compositions are used, the stacked oxide semiconductor films are preferably formed so that an upper film of the stacked films remains and thus a lower film of the stacked films is not exposed.

In this specification, a channel length L is a distance between a projecting portion which is one of the projecting portions of a source electrode layer extending in the channel length direction and overlaps with a conductive layer and an oxide semiconductor film and a projecting portion which is one of the projecting portions of a drain electrode layer extending in the channel length direction and overlaps with a conductive layer and the oxide semiconductor film (a horizontal distance when seen from the top surface). Thus, a channel length L of a transistor which does not have a depressed portion in an oxide semiconductor film and has a flat surface is considered as the same as a channel length L of a transistor which has a depressed portion in an oxide semiconductor film.

In the above structure, an insulating layer may be further provided so as to overlap with the source electrode layer and the drain electrode layer, and a gate insulating film may be provided over and in contact with the insulating layer. This insulating layer reduces parasitic capacitance formed between the gate electrode layer and the source electrode layer and parasitic capacitance formed between the gate electrode layer and the drain electrode layer. Further, this insulating layer is formed using a silicon oxide film, a silicon oxynitride film, or the like, and protects the source electrode layer and the drain electrode layer when the gate insulating film or the gate electrode layer is etched.

In the above structure, an insulating film containing gallium is used as a gate insulating film. Examples of the insulating film are a gallium oxide film (also represented by GaO_x ; X may be or may not be a natural number), a gallium zinc oxide film (also represented by $Ga_zZn_xO_y$ (X=1 to 5)), a Ga_2O_3 (Gd_2O_3) film, and an insulating In—Ga—Zn-based oxide film which has a low indium content. The insulating film containing gallium preferably contains a lot of oxygen, and thus the formation conditions of the insulating film containing gallium is made so that the insulating film containing

gallium contains a lot of oxygen or oxygen doping treatment is performed after the insulating film containing gallium is formed.

Note that the "oxygen doping" means that oxygen (which includes at least one of an oxygen radical, an oxygen atom, an oxygen molecule, ozone, an oxygen ion (oxygen molecular ion), and/or an oxygen cluster ion) is added to a bulk. Note that the term "bulk" is used in order to clarify that oxygen is added not only to a surface of a thin film but also to the inside of the thin film. In addition, "oxygen doping" includes "oxygen plasma doping" in which oxygen which is made to be plasma is added to a bulk.

A gas containing oxygen can be used for oxygen doping treatment. As the gas containing oxygen, oxygen, dinitrogen monoxide, nitrogen dioxide, carbon dioxide, carbon monoxide, and the like can be used. Further, a rare gas may be included in the gas containing oxygen for the oxygen doping treatment.

Depending on the conditions of the oxygen doping treatment, not only a film which is directly exposed to the oxygen doping treatment but also a film which is provided below the film can be doped with oxygen. That is, by forming the gate insulating film which is a gallium oxide film over the oxide semiconductor film and performing oxygen doping treatment, oxygen can be added not only to the gate insulating film but also to the oxide semiconductor film.

One embodiment of the present invention is a semiconductor device in which insulating films containing gallium such as a gallium oxide film, a gallium zinc oxide film, or a Ga_2O_3 (Gd_2O_3) film are provided below and over and in contact with an oxide semiconductor film to sandwich the oxide semiconductor film. The semiconductor device having the structure includes a conductive layer; an oxide insulating film over the conductive layer; a first insulating film containing gallium oxide over the oxide insulating film; an oxide semiconductor film which is over and in contact with the first insulating film and includes a channel formation region; a source electrode layer and a drain electrode layer which are over the oxide semiconductor film and are electrically connected to the oxide semiconductor film; a second insulating film containing gallium oxide over the oxide semiconductor film, the source electrode layer, and the drain electrode layer; and a gate electrode layer which is over the second insulating film and overlaps with the channel formation region.

In the above structure, the source electrode layer and the drain electrode layer are formed using a single-layer metal film. The source electrode layer and the drain electrode layer each include projecting portions extending in the channel length direction. Some of the projecting portions which overlap with the oxide semiconductor film overlap with the conductive layer.

In the above structure, the oxide semiconductor film preferably has a crystal structure. The oxide semiconductor film having a crystal structure is a single crystal film, a microcrystalline film, a polycrystalline film (also referred to as polycrystal), or a c-axis aligned crystalline oxide semiconductor (CAAC-OS) film.

The CAAC-OS film is not completely single crystal nor completely amorphous. The CAAC-OS film is an oxide semiconductor film including crystal parts. Note that in most cases, the crystal part fits inside a cube whose one side is less than 100 nm. In an image obtained with a transmission electron microscope (TEM), a boundary between adjacent crystal parts in the CAAC-OS film is not clearly detected. Further, with the TEM, a grain boundary in the CAAC-OS film is not found. Thus, in the CAAC-OS film, a reduction in electron mobility due to the grain boundary is suppressed.

In each of the crystal parts included in the CAAC-OS film, c-axes are aligned in the direction parallel to a normal vector of a surface where the CAAC-OS film is formed or a normal vector of a surface of the CAAC-OS film, triangular or hexagonal atomic arrangement which is seen from the direction perpendicular to the a-b plane is formed, and metal atoms are arranged in a layered manner or metal atoms and oxygen atoms are arranged in a layered manner when seen from the direction perpendicular to the c-axis. Note that, among crystal parts, the directions of the a-axis and the b-axis of one crystal part may be different from those of another crystal part. In this specification, a simple term "perpendicular" includes a range from 85° to 95° . In addition, a simple term "parallel" includes a range from -5° to 5° .

In the CAAC-OS film, distribution of crystal parts is not necessarily uniform. For example, in the formation process of the CAAC-OS film, in the case where crystal growth occurs from a surface side of the oxide semiconductor film, the proportion of crystal parts in the vicinity of the surface of the oxide semiconductor film is higher than that in the vicinity of the surface where the oxide semiconductor film is formed in some cases. By adding impurities to the CAAC-OS film, crystallinity of a crystal part in a region to which the impurities are added is reduced, and depending on the conditions for adding impurities, the region becomes a microcrystalline region or an amorphous region in some cases.

Since the c-axes of the crystal parts included in the CAAC-OS film are aligned in the direction parallel to a normal vector of a surface where the CAAC-OS film is formed or a normal vector of a surface of the CAAC-OS film, the directions of the c-axes may be different from each other depending on the shape of the CAAC-OS film (the cross-sectional shape of the surface where the CAAC-OS film is formed or the cross-sectional shape of the surface of the CAAC-OS film). Note that the direction of c-axis of the crystal portion is the direction parallel to a normal vector of the surface where the CAAC-OS film is formed or a normal vector of the surface of the CAAC-OS film. The crystal portion is formed by deposition or by performing treatment for crystallization such as heat treatment after deposition.

In an oxide semiconductor having a crystal portion such as the CAAC-OS, defects in the bulk can be further reduced and when the surface flatness of the oxide semiconductor is improved, mobility higher than that of an oxide semiconductor in an amorphous state can be obtained. In order to improve the surface flatness, the oxide semiconductor is preferably formed over a flat surface. Specifically, the oxide semiconductor may be formed over a surface with the average surface roughness (R_a) of less than or equal to 1 nm, preferably less than or equal to 0.3 nm, more preferably less than or equal to 0.1 nm.

With the use of the CAAC-OS film in a transistor, change in electrical characteristics of the transistor due to irradiation with visible light or ultraviolet light can be reduced. Thus, by using a CAAC-OS film as the oxide semiconductor film, it is possible to provide a highly reliable semiconductor device in which change in electrical characteristics of the transistor due to irradiation with visible light or ultraviolet light can be suppressed.

In the case where the oxide semiconductor film is a CAAC-OS film, the first insulating film and the second insulating film which are in contact with the CAAC-OS film preferably have a lower crystallinity than the oxide semiconductor film. Specifically, the first insulating film and the second insulating film are formed at a temperature lower than a film formation temperature of the CAAC-OS film or are formed using a rare gas (e.g., argon) as a film formation gas for sputtering.

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Oxygen doping treatment may be performed on the first insulating film containing gallium oxide so that the crystallinity is reduced, and an oxygen-excess region which contains oxygen whose proportion is higher than that in the stoichiometric composition of the first insulating film containing gallium oxide may be formed. For example, in the case of a gallium oxide film represented by Ga_2O_3 , the oxygen-excess region is GaO_x (x is greater than 1.5). The first insulating film including the oxygen-excess region prevents oxygen from being released from the oxide semiconductor film and effectively supplies oxygen to the oxide semiconductor film.

Oxygen doping treatment may be performed on the second insulating film containing gallium oxide so that the crystallinity is reduced, and an oxygen-excess region which contains oxygen whose proportion is higher than that in the stoichiometric composition of the second insulating film containing gallium oxide may be formed. The second insulating film including the oxygen-excess region prevents oxygen from being released from the oxide semiconductor film and effectively supplies oxygen to the oxide semiconductor film.

As the oxide semiconductor film, a semiconductor film containing gallium (e.g., an In—Ga—Zn-based oxide film) is used, and insulating films containing gallium (e.g., a gallium oxide film) are provided below and over and in contact with the oxide semiconductor film to sandwich the oxide semiconductor film. In such a case, the insulating films provided below and over the oxide semiconductor film contain the same constituent material as that of the oxide semiconductor film, and thus the interface state between the oxide semiconductor film and the insulating films can be excellent, which gives stable electrical characteristics. By providing the insulating films, which contain gallium oxide, below and over and in contact with the oxide semiconductor film to sandwich the oxide semiconductor film, the insulating films can prevent impurities such as nitrogen and a metal element, which might affect the oxide semiconductor film, from entering from the outside by diffusion. Thus, by providing the insulating films containing gallium oxide to sandwich or cover the oxide semiconductor film, the composition and the purity of the covered oxide semiconductor film are kept constant, which gives stable electrical characteristics.

The source electrode layer and the drain electrode layer each having a cross-sectional shape with which disconnection of the gate insulating film is unlikely to occur even when the gate insulating film has a thickness less than or equal to 20 nm or the oxide semiconductor film has a thickness less than or equal to 30 nm. Further, the source electrode layer and the drain electrode layer are formed over the oxide semiconductor film using a single-layer metal film, and electric-field concentration which might occur in end portions of the source electrode layer and the drain electrode layer is reduced.

By using insulating films containing gallium oxide which are below and over and in contact with the oxide semiconductor film to sandwich the oxide semiconductor film, electrical characteristics become stable and reliability can be improved.

BRIEF DESCRIPTION OF THE DRAWINGS

FIGS. 1A to 1D are cross-sectional views illustrating manufacturing steps of one embodiment of the present invention.

FIGS. 2A to 2C are cross-sectional views illustrating manufacturing steps of one embodiment of the present invention.

FIGS. 3A to 3C are cross-sectional views of embodiments of the present invention.

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FIGS. 4A to 4E are cross-sectional views illustrating manufacturing steps of one embodiment of the present invention.

FIGS. 5A to 5C are cross-sectional views of embodiments of the present invention.

FIGS. 6A and 6B are a cross-sectional view and a top view illustrating one embodiment of the present invention.

FIGS. 7A and 7B are a cross-sectional view and a circuit diagram illustrating one embodiment of a semiconductor device.

FIGS. 8A to 8C are a cross-sectional view and circuit diagrams illustrating one embodiment of a semiconductor device.

FIG. 9 is a circuit diagram illustrating one embodiment of a semiconductor device.

FIG. 10 is a perspective view illustrating one embodiment of a semiconductor device.

FIGS. 11A to 11C are block diagrams illustrating one embodiment of a semiconductor device.

FIGS. 12A to 12C are drawings illustrating an electronic device.

FIGS. 13A to 13C are drawings illustrating electronic devices.

FIG. 14 is a cross-sectional view illustrating one embodiment of the invention.

FIGS. 15A to 15C are cross-sectional views of embodiments of the present invention and a cross-sectional image of an end portion of an electrode layer.

FIGS. 16A and 16B are cross-sectional images of end portions of electrode layers.

DETAILED DESCRIPTION OF THE INVENTION

Hereinafter, embodiments of the present invention are described in detail with reference to the accompanying drawings. However, the present invention is not limited to the description below, and it is easily understood by those skilled in the art that modes and details disclosed herein can be modified in various ways without departing from the spirit and the scope of the present invention. Therefore, the present invention is not construed as being limited to description of the embodiments.

(Embodiment 1)

In this embodiment, one embodiment of a semiconductor device and a method for manufacturing the semiconductor device is described with reference to FIGS. 1A to 1D. In this embodiment, an example of a method for manufacturing a transistor including an oxide semiconductor film is described.

A conductive film is formed over a substrate 400 having an insulating surface by a sputtering method, an evaporation method, or the like. The conductive film is etched so that a conductive layer 491 is formed.

There is no particular limitation on a substrate that can be used as the substrate 400 having an insulating surface as long as it has heat resistance enough to withstand heat treatment performed later. For example, a glass substrate of barium borosilicate glass, aluminoborosilicate glass, or the like, a ceramic substrate, a quartz substrate, or a sapphire substrate can be used. A single crystal semiconductor substrate or a polycrystalline semiconductor substrate of silicon, carbon silicon, or the like; a compound semiconductor substrate of silicon germanium or the like; an SOI substrate; or the like can be used as the substrate 400, or the substrate provided with a semiconductor element can be used as the substrate 400.

The conductive layer 491 can be formed using a metal material such as molybdenum, titanium, tantalum, tungsten,

aluminum, copper, chromium, neodymium, or scandium or an alloy material which contains any of these materials as its main component. Alternatively, a semiconductor film typified by a polycrystalline silicon film doped with an impurity element such as phosphorus, or a silicide film such as a nickel silicide film may be used as the conductive layer 491. The conductive layer 491 may have a single-layer structure or a stacked-layer structure.

The conductive layer 491 can also be formed using a conductive material such as indium oxide-tin oxide, indium oxide containing tungsten oxide, indium zinc oxide containing tungsten oxide, indium oxide containing titanium oxide, indium tin oxide containing titanium oxide, indium oxide-zinc oxide, or indium tin oxide to which silicon oxide is added. It is also possible that the conductive layer 491 has a stacked structure of the above conductive material and the above metal material.

In order to obtain a normally-off switching element, it is preferable that the threshold voltage of the transistor is made positive by using a material having a work function of 5 eV (electron volts) or higher, preferably 5.5 eV or higher, for a gate electrode layer. Specifically, a material which includes an In—N bond and has a specific resistivity of $1 \times 10^{10-1} \Omega \cdot \text{cm}$ to $1 \times 10^{10-4} \Omega \cdot \text{cm}$, preferably $5 \times 10^{10-2} \Omega \cdot \text{cm}$ to $1 \times 10^{10-4} \Omega \cdot \text{cm}$, is used for the gate electrode layer. Examples of the material are an In—Ga—Zn-based oxide film containing nitrogen, an In—Sn—O film containing nitrogen, an In—Ga—O film containing nitrogen, an In—Zn—O film containing nitrogen, an In—O film containing nitrogen, and a metal nitride film (e.g., an InN film).

Next, an oxide insulating film 480 is formed over the substrate 400 and the conductive layer 491 (see FIG. 1A). The oxide insulating film 480 has a projecting portion reflecting the shape of the conductive layer 491 on its surface.

The oxide insulating film 480 can be formed by a plasma CVD method, a sputtering method, or the like, using silicon oxide, silicon oxynitride, aluminum oxide, aluminum oxynitride, hafnium oxide, gallium oxide, gallium oxide zinc, zinc oxide, or a mixed material of any of these materials. The oxide insulating film 480 may have either a single-layer structure or a stacked-layer structure.

A silicon oxide film formed by a sputtering method is used as the oxide insulating film 480 in this embodiment. Alternatively, a silicon oxynitride film formed by a plasma CVD method may be used.

Next, treatment for adding an oxygen 431 (oxygen doping treatment) is performed on the oxide insulating film 480 having the projecting portion on its surface, so that an oxygen-excess region 481 is formed in the vicinity of the bottom surface of the oxide insulating film 480 and in the vicinity of the conductive layer 491. Thus, an oxide insulating film 484 having the oxygen-excess region 481 is formed (see FIG. 1B). Note that in the drawing, the oxygen-excess region 481 is illustrated by a dotted line, and the dotted line schematically indicates a center of distribution of the added oxygen.

At least any of an oxygen radical, an oxygen atom, an oxygen molecule, ozone, an oxygen ion (an oxygen molecular ion) and/or an oxygen cluster ion may be included in the oxygen 431.

Introducing the oxygen 431 into the oxide insulating film 480 can be performed by, for example, an ion implantation method, an ion doping method, a plasma immersion ion implantation method, plasma treatment, or the like. Note that as an ion implantation method, a gas cluster ion beam may be used. The oxygen 431 may be introduced into the entire surface of the substrate 400 at a time. Alternatively, a linear ion beam may be used, for example. In the case of using a

linear ion beam, relative movement (scanning) of the substrate or the ion beam enables the oxygen 431 to be introduced into the entire surface of the oxide insulating film 480.

As a supply gas of the oxygen 431, a gas containing oxygen (O) can be used; for example, an O₂ gas, an N₂O gas, a CO₂ gas, a CO gas, or an NO₂ gas can be used. Note that a rare gas (e.g., an Ar gas) may be contained in the supply gas of the oxygen.

In the case where oxygen is added by an ion implantation method, the dose of the oxygen 431 is preferably $0.5 \times 10^{16} \text{ cm}^{-2}$ or higher and $5 \times 10^{16} \text{ cm}^{-2}$ or lower (e.g., $1 \times 10^{16} \text{ ions/cm}^2$), and the acceleration energy is preferably 50 eV or higher and 70 eV or lower (e.g., 50 eV). The oxygen content in an oxide insulating film 436 including the oxygen-excess region 481 on which the oxygen doping treatment has been performed is preferably higher than that in the stoichiometric composition of the oxide insulating film 436. Such a region containing oxygen in excess of the stoichiometric composition preferably exist in the oxygen-excess region 481. The depth at which the oxygen 431 is implanted may be adjusted as appropriate by implantation conditions.

Next, planarization treatment is performed on the oxide insulating film 484 including the oxygen-excess region 481 so that the projecting portion of the top surface of the oxide insulating film 484 is removed. The oxide insulating film 480 over the conductive layer 491 is selectively removed, so that the surface of the oxide insulating film 480 is planarized. Accordingly, the planarized oxide insulating film 436 is formed (see FIG. 1C).

By the planarization treatment, the oxide insulating film 480 over the conductive layer 491 is selectively removed to be thin, whereby the distance between the oxygen-excess region 481 over the conductive layer 491 and the top surface of the oxide insulating film 480 becomes shorter. In contrast, a region of the oxide insulating film 480 in which the conductive layer 491 does not exist is hardly removed, and the oxygen-excess region 481 exists in the vicinity of the bottom surface of the oxide insulating film 480. Thus, in the oxide insulating film 436, the oxygen-excess region 481 is provided at a shallow position from the top surface of the oxide insulating film in the region where the conductive layer 491 exists and is provided at a deep position from the top surface of the oxide insulating film in another region (the region where the conductive layer 491 does not exist).

Since the oxygen-excess region 481 can be provided close to the oxide semiconductor film in a part of the oxide insulating film 436 over which the oxide semiconductor film is provided in a later step and which overlaps with the conductive layer 491, oxygen can be efficiently supplied from the oxygen-excess region 481 to the oxide semiconductor film. Supply of oxygen can be promoted by heat treatment.

In the oxide insulating film 436, the oxygen-excess region 481 is provided apart from the top surface of the oxide insulating film 436 in a region other than the region below the oxide semiconductor film to which oxygen is required to be supplied, that is, in the vicinity of the bottom surface of the oxide insulating film 436. Thus, in the case where heat treatment is performed, in particular, unnecessary release of oxygen from the top surface of the oxide insulating film 436 can be suppressed, and the oxide insulating film 436 can be kept in an oxygen excess state.

The addition of the oxygen 431 to the oxide insulating film 480 is described as an example in this embodiment; however, the addition of the oxygen 431 to the oxide insulating film 480 can be omitted as long as the oxide insulating film 480 contains sufficient oxygen shortly after the formation.

The planarization treatment may be, but not particularly limited to, polishing treatment (such as chemical mechanical polishing (CMP)), dry etching treatment, or plasma treatment.

Next, an oxide semiconductor film **403** is formed over the oxide insulating film **436**. As a material of the oxide semiconductor film **403**, for example, the following can be used: a two-component metal oxide such as an In—Zn-based oxide, an In—Mg-based oxide, or an In—Ga-based oxide, a three-component metal oxide such as an In—Ga—Zn-based oxide (also referred to as IGZO), an In—Sn—Zn-based oxide, an In—Hf—Zn-based oxide, an In—La—Zn-based oxide, an In—Ce—Zn-based oxide, an In—Pr—Zn-based oxide, an In—Nd—Zn-based oxide, an In—Sm—Zn-based oxide, an In—Eu—Zn-based oxide, an In—Gd—Zn-based oxide, an In—Tb—Zn-based oxide, an In—Dy—Zn-based oxide, an In—Ho—Zn-based oxide, an In—Er—Zn-based oxide, an In—Tm—Zn-based oxide, an In—Yb—Zn-based oxide, or an In—Lu—Zn-based oxide, or a four-component metal oxide such as an In—Sn—Ga—Zn-based oxide, an In—Hf—Ga—Zn-based oxide, an In—Sn—Al—Zn-based oxide, or an In—Sn—Hf—Zn-based oxide.

Note that here, for example, an In—Ga—Zn-based oxide means an oxide containing In, Ga, and Zn, and there is no limitation on the composition ratio of In, Ga, and Zn. Further, the In—Ga—Zn-based oxide semiconductor may contain a metal element other than In, Ga, and Zn.

In this embodiment, as a target for forming the oxide semiconductor film **403** by a sputtering method, an oxide target containing In, Ga, and Zn in an atomic ratio of In:Ga:Zn=3:1:2 is used to form an In—Ga—Zn-based oxide film (IGZO film) having a thickness of 5 nm or greater and 30 nm or smaller.

The relative density (filling factor) of the metal oxide target is greater than or equal to 90% and less than or equal to 100%, preferably greater than or equal to 95% and less than or equal to 99.9%. With use of the metal oxide target with high filling factor, a dense oxide semiconductor film can be formed.

It is preferable that a high-purity gas from which impurities such as hydrogen, water, a hydroxyl group, and hydride are removed be used as a sputtering gas for the formation of the oxide semiconductor film **403**.

The substrate is held in a deposition chamber kept under reduced pressure. Then, a sputtering gas in which hydrogen and moisture are removed is introduced into the deposition chamber from which remaining moisture is being removed, so that the oxide semiconductor film **403** is formed over the oxide insulating film **436** with the use of the target. To remove moisture remaining in the deposition chamber, an entrapment vacuum pump such as a cryopump, an ion pump, or a titanium sublimation pump is preferably used. As an exhaustion unit, a turbo molecular pump to which a cold trap is added may be used. In the deposition chamber which is evacuated with the cryopump, for example, a hydrogen atom, a compound containing a hydrogen atom, such as water (H₂O), (further preferably, also a compound containing a carbon atom), and the like are removed, whereby the concentration of impurities in the oxide semiconductor film **403** formed in the deposition chamber can be reduced.

The oxide semiconductor film **403** can be formed by processing a film-shaped oxide semiconductor film into an island shape by a photolithography process.

A resist mask for forming the island-shaped oxide semiconductor film **403** may be formed by an inkjet method. Formation of the resist mask by an inkjet method needs no photomask; thus, manufacturing cost can be reduced.

It is preferable that the oxide semiconductor film **403** be the one which is highly purified and hardly contain impurities such as copper. In the process for manufacturing a transistor **440a**, steps in which these impurities are not mixed or attached to the surface of the oxide semiconductor film **403** are preferably selected as appropriate. In the case where the impurities are attached to the surface of the oxide semiconductor film **403**, the impurities on the surface of the oxide semiconductor film **403** are preferably removed by exposure to oxalic acid or dilute hydrofluoric acid or plasma treatment (such as N₂O plasma treatment). Specifically, the concentration of copper in the oxide semiconductor film **403** is lower than or equal to 1×10^{18} atoms/cm³, preferably lower than or equal to 1×10^{17} atoms/cm³.

Heat treatment may be performed in order to promote supply of oxygen from the oxide insulating film **436** to the oxide semiconductor film **403**.

Next, a source electrode layer **405a** and a drain electrode layer **405b** which are electrically connected to the oxide semiconductor film **403** are formed. A variety of circuits can be formed by connection with another transistor or element with the use of the source electrode layer **405a** and the drain electrode layer **405b**.

The source electrode layer **405a** and the drain electrode layer **405b** can be formed in such a manner that a conductive film is formed by a sputtering method, an evaporation method, or the like and then is processed by an etching method.

As the conductive film used for the source electrode layer **405a** and the drain electrode layer **405b**, for example, a metal film containing an element selected from Al, Cr, Cu, Ta, Ti, Mo, and W, or a metal nitride film containing any of the above elements as a component (e.g., a titanium nitride film, a molybdenum nitride film, or a tungsten nitride film) can be used.

In this embodiment, a single-layer tungsten film is used, a resist mask is formed over the tungsten film, first etching is performed to remove the tungsten film to approximately half the thickness so that the tungsten film partly has a small thickness, and ashing is performed on the resist mask for reducing the area of the resist mask. After that, second etching is performed with the resist mask, which is reduced in size, so that the source electrode layer **405a** and the drain electrode layer **405b** each including projecting portions when seen in cross-section as illustrated in FIG. 1D are formed.

Subsequently, the resist mask, which is reduced in size, is removed. A cross-sectional view at this stage corresponds to FIG. 1D.

Next, a gate insulating film **402** is formed to cover the oxide semiconductor film **403**, the source electrode layer **405a**, and the drain electrode layer **405b**.

The gate insulating film **402** has a thickness greater than or equal to 1 nm and less than or equal to 20 nm, for example, and can be formed by a sputtering method, an MBE method, a CVD method, a pulsed laser deposition method, an ALD method, or the like as appropriate. The gate insulating film **402** may be formed with a sputtering apparatus which performs film deposition on surfaces of a plurality of substrates set substantially perpendicular to a surface of a sputtering target.

A material of the gate insulating film **402** can be a silicon oxide film, a gallium oxide film, a gallium oxide zinc film, a Ga₂O₃ (Gd₂O₃) film, a zinc oxide film, an aluminum oxide film, a silicon nitride film, a silicon oxynitride film, an aluminum oxynitride film, or a silicon nitride oxide film. As another material of the gate insulating film **402**, an In—Ga—Zn-based oxide film having an insulating property can be

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given. The In—Ga—Zn-based oxide film having an insulating property may be formed under the following conditions: an oxide target containing In, Ga, and Zn in an atomic ratio of In:Ga:Zn=1:3:2 is used, the substrate temperature is room temperature, and a sputtering gas is an argon gas or a mixed gas of argon and oxygen.

In this embodiment, a gallium oxide film formed by a sputtering method is used as the gate insulating film 402. By using the gallium oxide film as the gate insulating film 402, the gate insulating film 402 contains the same constituent material as that of the oxide semiconductor film 403, and thus the interface state between the oxide semiconductor film 403 and the gate insulating film 402 can be excellent, which gives stable electrical characteristics.

Next, a conductive film is formed over the gate insulating film 402 by a sputtering method, an evaporation method, or the like. The conductive film is etched so that gate electrode layers 401a and 401b are formed.

The gate electrode layers 401a and 401b can be formed using a metal material such as molybdenum, titanium, tantalum, tungsten, aluminum, copper, chromium, neodymium, or scandium or an alloy material which contains any of these materials as its main component. Alternatively, a semiconductor film typified by a polycrystalline silicon film doped with an impurity element such as phosphorus, or a silicide film such as a nickel silicide film may be used as the gate electrode layers 401a and 401b. The gate electrode layers 401a and 401b may have a single-layer structure or a stacked-layer structure.

In this embodiment, a metal oxide film containing nitrogen (an In—Ga—Zn-based oxide film containing nitrogen) is used as the gate electrode layer 401a over and in contact with the gate insulating film 402, and a tungsten film is formed over the gate electrode layer 401a as the gate electrode layer 401b. The use of the metal oxide film containing nitrogen as the gate electrode layer 401a enables the transistor to have a positive threshold voltage.

Through the above steps, the transistor 440a of this embodiment can be manufactured (see FIG. 2A). The transistor 440a is an example of a top-gate transistor. FIG. 2A is a cross-sectional view of the transistor 440a in the channel length direction.

The conductive layer 491 provided in the oxide insulating film 436 including the oxygen-excess region 481 overlaps with the gate electrode layers 401a and 401b with a channel formation region positioned therebetween, and controls the electrical characteristics of the transistor 440a.

The conductive layer 491 serves as a second gate electrode layer (what we call a back gate) which controls the electrical characteristics of the transistor 440a. For example, by setting the potential of the conductive layer 491 to GND (or a fixed potential), the threshold voltage of the transistor 440a is increased, so that the transistor 440a can be normally off. The gate electrode layers 401a and 401b overlap with part of the source electrode layer 405a and part of the drain electrode layer 405b. Since some of the projecting portions of the source electrode layer 405a and the drain electrode layer 405b have shapes with which coverage with the gate insulating film 402 can be improved, electric-field concentration is reduced, which contributes to improvement in the electrical characteristics and reliability of the transistor.

Next, an insulating film 407 covering the gate electrode layers 401a and 401b is formed (see FIG. 2B). The insulating film 407 functions as a barrier film (protective film) having a high property of preventing oxygen from being released from the oxide semiconductor film 403 or the gate insulating film 402.

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The insulating film 407 functioning as a barrier film is preferably a fine film which can prevent impurities such as hydrogen and moisture from entering to the oxide semiconductor film 403.

As the insulating film 407 functioning as a barrier film, for example, an inorganic insulating film such as a gallium oxide film, a gallium oxide zinc film, a Ga_2O_3 (Gd_2O_3) film, a silicon oxide film, a silicon oxynitride film, an aluminum oxide film, an aluminum oxynitride film, a silicon nitride film, an aluminum nitride film, a silicon nitride oxide film, an aluminum nitride oxide film, or a zinc oxide film can be used. The insulating film 407 may have a single layer or a stacked layer. The insulating film 407 functioning as a barrier film can be formed by a plasma CVD method, a sputtering method, a CVD method using a deposition gas, or an MBE method.

Next, an interlayer insulating film 485 is formed over the insulating film 407. The interlayer insulating film 485 may be a single layer or a stacked layer, and an inorganic insulating film such as a silicon oxide film, a silicon oxynitride film, an aluminum oxide film, an aluminum oxynitride film, a silicon nitride film, an aluminum nitride film, a silicon nitride oxide film, an aluminum nitride oxide film, a gallium oxide film, or a gallium oxide zinc film can be used.

FIG. 2C is a cross-sectional view illustrating the steps up to and including the formation of an embedded wiring in the interlayer insulating film 485. A contact hole reaching the source electrode layer 405a is formed in the interlayer insulating film 485, a first barrier metal film 486 is formed, and a copper film or a copper alloy film is formed thereover so as to form a low-resistance conductive layer 487. Then, polishing is performed for planarization, and a second barrier metal film 488 is formed so as to protect the exposed low-resistance conductive layer 487. The embedded wiring includes the first barrier metal film 486, the second barrier metal film 488, and the low-resistance conductive layer 487 surrounded by the first barrier metal film 486 and the second barrier metal film 488.

Each of the first barrier metal film 486 and the second barrier metal film 488 may be formed using a conductive material which suppresses diffusion of copper contained in the low-resistance conductive layer 487. Examples of the conductive material are a tantalum nitride film, a molybdenum nitride film, and a tungsten nitride film.

Through the above steps, a semiconductor device having a multilayer structure in which another semiconductor element, another wiring, or the like is formed over the transistor 440a can be manufactured. The semiconductor element, the wiring, or the like which is provided over the transistor 440a can be electrically connected to the embedded wiring.

The cross-sectional structure of the transistor 440a described in this embodiment is merely an example, and is not limited as long as the cross-sectional shapes of the source electrode layer 405a and the drain electrode layer 405b are the same as those in this embodiment. Although the transistor 440a is a MOSFET here, an insulated gate bipolar transistor (IGBT), a metal semiconductor field effect transistor (MESFET), or the like can be used as the transistor 440a. In the case where an IGBT is used as the transistor 440a, a source electrode layer corresponds to an emitter terminal and a drain electrode layer corresponds to a collector terminal. Examples of cross-sectional structures of other transistors are given below.

A transistor 440b illustrated in FIG. 3A has a structure in which the thickness of a region of the oxide semiconductor film 403 which does not overlap with the source electrode layer 405a and the drain electrode layer 405b and overlaps with the conductive layer 491 is smaller than the thickness of

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regions of the oxide semiconductor film **403** which overlap with the source electrode layer **405a** and the drain electrode layer **405b**. The structure in FIG. 3A is the same as that in FIG. 2B except a depressed portion is formed in the channel formation region. Thus, detailed description thereof is omitted here.

The oxide semiconductor film **403** of the transistor **440b** in FIG. 3A can be formed in such a manner that, after the source electrode layer **405a** and the drain electrode layer **405b** are formed, etching is performed with the use of the source electrode layer **405a** and the drain electrode layer **405b** as masks. The depressed portion formed in the channel formation region as illustrated in FIG. 3A makes it possible to electric-field concentration which might occur between the source electrode layer **405a** and the drain electrode layer **405b** to be reduced.

A transistor **440c** illustrated in FIG. 3B has a stacked-layer structure in which a second oxide semiconductor film **403b** having a composition different from that of a first oxide semiconductor film **403a** is formed over the first oxide semiconductor film **403a**. The second oxide semiconductor film **403b** includes a depressed portion. The structure in FIG. 3B is the same as that in FIG. 3A except the transistor **440c** has a stacked-layer structure. Thus, detailed description thereof is omitted here.

As the first oxide semiconductor film **403a**, an In—Ga—Zn-based oxide film formed with a target having an atomic ratio of In:Ga:Zn=3:1:2 is used. The first oxide semiconductor film **403a** preferably contains more In than Ga and Zn in an atomic ratio. As the second oxide semiconductor film **403b**, an In—Ga—Zn-based oxide film formed with a target having an atomic ratio of In:Ga:Zn=1:1:1 is used.

In the case where stacked oxide semiconductor films having different compositions are used, the stacked oxide semiconductor films are formed so that an upper film of the stacked films remains and thus a lower film of the stacked films (the first oxide semiconductor film **403a** in this embodiment) is not exposed to a bottom of the depressed portion.

An In—Ga—Zn-based oxide film formed with a target having an atomic ratio of In:Ga:Zn=3:1:2 is used for a channel formation region of the transistor **440c** in FIG. 3B, and thus field-effect mobility can be improved.

A transistor **440d** in FIG. 3C is an example in which an insulating film **437** containing gallium oxide is provided between an oxide insulating film **493** and the stacked oxide semiconductor films, and a conductive layer **492** does not overlap with the channel formation region. Oxygen is supplied to the stacked oxide semiconductor films from the insulating film **437** containing gallium oxide, which includes an oxygen-excess region containing oxygen whose proportion is higher than that in the stoichiometric composition. Thus, oxygen doping treatment is not performed on the oxide insulating film **493**. Except for these different points, the structure in FIG. 3C is the same as that in FIG. 3B. Thus, detailed description thereof is omitted here.

In the case where the threshold voltage of the transistor **440d** is increased and the transistor **440d** is a normally-off transistor shortly after the formation thereof, as illustrated in FIG. 3C, the conductive layer **492** does not necessarily overlap with the channel formation region. In the case where the transistor **440d** is not required to be a normally-off transistor depending on the circuit configuration, only the transistor can be used as a normally-on transistor.

The insulating film **437** containing gallium oxide can be etched with the use of the photomask which is also used for the stacked oxide semiconductor films. The pattern shape of the insulating film **437** when seen from the top surface is the

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same as that of the stacked oxide semiconductor films. Thus, the structure in FIG. 3C can be obtained using the same number of masks as the structure in FIG. 3B.

In the transistor **440d**, in the case where an insulating film containing gallium oxide is used as the gate insulating film **402**, the stacked oxide semiconductor films can be sandwiched by insulating films containing gallium oxide which are provided below and over and in contact with the oxide semiconductor films. The insulating film containing gallium oxide prevents oxygen from being released from the stacked oxide semiconductor films and effectively supplies oxygen to the stacked oxide semiconductor films. The insulating films provided below and over the oxide semiconductor films contain the same constituent material as that of the oxide semiconductor films, and thus the interface state between the oxide semiconductor films and the insulating films can be excellent, which gives stable electrical characteristics.

The structures of the transistors illustrated in FIG. 2B and FIGS. 3A to 3C are partly different from one another; however, the present invention is not limited to these structures, and various combinations are possible. For example, by combining the planarized oxide semiconductor film **403** illustrated in FIG. 2B and the insulating film **437** containing gallium oxide illustrated in FIG. 3C, a transistor of one embodiment of the present invention may have a structure in which the planarized oxide semiconductor film **403** is provided over the insulating film **437** containing gallium oxide. (Embodiment 2)

In this embodiment, an example of a method for manufacturing a transistor is described below; the method allows reduction in parasitic capacitance that is formed among a gate electrode layer, a gate insulating film, and a source electrode layer which overlaps with the gate electrode layer with the gate insulating film provided therebetween and parasitic capacitance that is formed among the gate electrode layer, the gate insulating film, and a drain electrode layer which overlaps with the gate electrode layer with the gate insulating film provided therebetween. Part of steps in a manufacturing process is the same as that in Embodiment 1, and thus the detailed description of the part of the steps is omitted.

First, steps up to and including the step in FIG. 1C, which is described in Embodiment 1, are performed. That is, the conductive layer **491** is formed over the substrate **400**, and the oxide insulating film **436** including the oxygen-excess region **481** is formed. A cross-sectional view at this stage is shown in FIG. 4A. Note that FIG. 4A is the same as FIG. 1C.

Then, the first oxide semiconductor film **403a** is formed over the oxide insulating film **436**, and the second oxide semiconductor film **403b** is formed over the first oxide semiconductor film **403a**. The first oxide semiconductor film **403a** and the second oxide semiconductor film **403b** are successively formed without exposure to the air.

As the first oxide semiconductor film **403a**, an In—Ga—Zn-based oxide film formed with a target having an atomic ratio of In:Ga:Zn=3:1:2 is used. The first oxide semiconductor film **403a** contains more In than Ga and Zn in an atomic ratio. As the second oxide semiconductor film **403b**, an In—Ga—Zn-based oxide film formed with a target having an atomic ratio of In:Ga:Zn=1:1:1 is used.

Next, the oxide semiconductor films are processed into island-shaped oxide semiconductor films by a photolithography process. After that, a conductive film is formed by a sputtering method, an evaporation method, or the like.

Next, resist masks **408a** and **408b** are formed over the conductive film, and etching is performed to remove the conductive film to approximately half the thickness so that the conductive film partly has a small thickness. Thus, a conduc-

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tive film **406** which partly has a small thickness is formed. A cross-sectional view at this stage is illustrated in FIG. **4B**.

Subsequently, the resist masks **408a** and **408b** are removed and then, a protective layer **409** is formed over the conductive film **406** which partly has a small thickness (see FIG. **4C**). This protective layer **409** is provided to protect part of the conductive film in later etching of the gate insulating film **402**. This protective layer **409** is formed using a silicon oxide film, a silicon oxynitride film, an aluminum oxide film, an aluminum oxynitride film, a silicon nitride film, an aluminum nitride film, a silicon nitride oxide film, an aluminum nitride oxide film, or the like. Note that is preferable that the protective layer **409** be formed using a material different from that of the gate insulating film **402** and etching selectivity of the gate insulating film **402** to the protective layer **409** be high. In this embodiment, a silicon oxide film formed by a sputtering method is used.

Next, a resist mask is formed over the protective layer **409**, and then the source electrode layer **405a** and the drain electrode layer **405b** each including projecting portions when seen in cross-section as illustrated in FIG. **4D** are formed. In the formation of the source electrode layer **405a** and the drain electrode layer **405b**, the protective layer **409** is also etched, and a first protective layer **410a** which overlaps with and is in contact with the source electrode layer **405a** and a second protective layer **410b** which overlaps with and is in contact with the drain electrode layer **405b** are formed. A cross-sectional view at the stage in which the resist mask is removed is illustrated in FIG. **4D**.

Then, the gate insulating film **402** covering the first oxide semiconductor film **403a**, the second oxide semiconductor film **403b**, the first protective layer **410a**, and the second protective layer **410b** is formed. As a material of the gate insulating film **402**, a film containing gallium oxide, typically a gallium oxide film, is used in this embodiment. Even in the case where the film containing gallium oxide has a small thickness such as 20 nm or smaller, the film prevents impurities such as nitrogen from entering the first oxide semiconductor film **403a** or the second oxide semiconductor film **403b** provided below the film when or after a metal oxide film containing nitrogen is formed by a sputtering method or the like in a later step.

Next, a conductive film is formed over the gate insulating film **402** by a sputtering method, an evaporation method, or the like. The conductive film is etched so that the gate electrode layers **401a** and **401b** are formed. Next, part of the gate insulating film **402** is removed with the use of the gate electrode layers **401a** and **401b** as masks. When part of the gate insulating film **402** is removed, the first protective layer **410a** and the second protective layer **410b** function as etching stoppers, that is, protect the source electrode layer **405a** and the drain electrode layer **405b** from etching treatment.

In this embodiment, a metal oxide film containing nitrogen (an In—Ga—Zn-based oxide film containing nitrogen) is used as the gate electrode layer **401a** over and in contact with the gate insulating film **402**, and a tungsten film is formed over the metal oxide as the gate electrode layer **401b**.

Through the above steps, a transistor **441a** of this embodiment can be manufactured. Lastly, the insulating film **407** is formed so that the insulating film **407** covers the gate electrode layers **401a** and **401b** and is in contact with the first protective layer **410a** and the second protective layer **410b** (see FIG. **4E**). The insulating film **407** functions as a barrier film having a high property of preventing oxygen from being released from the first oxide semiconductor film **403a**, the second oxide semiconductor film **403b**, or the gate insulating film **402**. The transistor **441a** is an example of a top-gate

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transistor. FIG. **4E** is a cross-sectional view of the transistor **441a** in the channel length direction.

In the transistor **441a** in FIG. **4E**, even though the gate electrode layers **401a** and **401b** overlap with part of the source electrode layer **405a** and part of the drain electrode layer **405b**, since the first protective layer **410a** and the second protective layer **410b** are provided over and in contact with the source electrode layer **405a** and the drain electrode layer **405b**, respectively, parasitic capacitance of this portion is smaller than that of the transistor **440a** in Embodiment 1.

The cross-sectional structure of the transistor **441a** described in this embodiment is merely an example. The cross-sectional structure is not limited as long as the cross-sectional shapes of the source electrode layer **405a** and the drain electrode layer **405b** are the same as those in this embodiment. An example of a cross-sectional structure of another transistor is given below.

A transistor **441b** in FIG. **5A** is an example in which an insulating film **438** containing gallium oxide is provided between the oxide insulating film **436** and the first oxide semiconductor film **403a**.

The transistor **441b** in FIG. **5A** includes the insulating film **438** containing gallium oxide in contact with bottom surfaces of the source electrode layer **405a** and the drain electrode layer **405b**. The insulating film **438** containing gallium oxide functions as an etching stopper for protecting the oxide insulating film **436** in etching of the gate insulating film **402**. The insulating film **407** is in contact with the insulating film **438** containing gallium oxide in the periphery region of the transistor.

The structure in FIG. **5A** is the same as that in FIG. **4E** except the insulating film **438** containing gallium oxide is provided between the oxide insulating film **436** and the first oxide semiconductor film **403a**. Thus, detailed description thereof is omitted here.

A transistor **441c** in FIG. **5B** includes the insulating film **438** containing gallium oxide which is provided between the oxide insulating film **436** and the first oxide semiconductor film **403a** and is partly in contact with the gate insulating film **402**. The transistor in FIG. **5B** has the same structure as that in FIG. **5A** except for the top shape of the gate insulating film **402**. Thus, detailed description thereof is omitted here.

In the transistor **441c**, since the gate insulating film **402** contains gallium oxide, the first oxide semiconductor film **403a**, the second oxide semiconductor film **403b**, the source electrode layer **405a**, and the drain electrode layer **405b** are covered with insulating films containing gallium oxide. Thus, oxygen is prevented from being released all around from the stacked oxide semiconductor films.

A transistor **441d** illustrated in FIG. **5C** includes the insulating film **437** containing gallium oxide between an insulating film **434** and the first oxide semiconductor film **403a**, and has a stacked-layer structure in which the second oxide semiconductor film **403b** having a composition different from that of the first oxide semiconductor film **403a** is formed over the first oxide semiconductor film **403a**. The second oxide semiconductor film **403b** includes a depressed portion. Oxygen is supplied to the stacked oxide semiconductor films from the insulating film **437** containing gallium oxide, which includes an oxygen-excess region where the proportion of oxygen is higher than that in the oxide semiconductor film in the stoichiometric composition exists. Thus, oxygen doping treatment is not performed on the oxide insulating film **435**. The insulating film **434** covering the conductive layer **491** is formed, an oxide insulating film **435** is polished to expose

part of the insulating film **434**, and the insulating film **437** containing gallium oxide is provided so as to overlap with the exposed portion.

The insulating film **434** is a barrier film, and is formed using an inorganic insulating film such as an aluminum oxide film, an aluminum oxynitride film, a silicon nitride film, an aluminum nitride film, a silicon nitride oxide film, an aluminum nitride oxide film, a gallium oxide film, or a gallium zinc oxide film.

The insulating film **434** is a silicon oxide film or a silicon oxynitride film obtained by a plasma CVD method.

The transistor **441d** in FIG. **5C** has the same structure as that in FIG. **5A** except the insulating film **437** containing gallium oxide, the second oxide semiconductor film **403b** including a depressed portion, and the insulating film **434** are provided and oxygen doping treatment is not performed. Thus, detailed description thereof is omitted here.

A transistor **441e** in FIG. **6A** has the same structure as that in FIG. **5C** except the second oxide semiconductor film **403b** has a flat top surface. Thus, detailed description thereof is omitted here.

FIG. **6B** illustrates an example of a top view of the transistor **441e**. A cross-sectional view taken along a chain line A-B in FIG. **6B** corresponds to FIG. **6A**. As illustrated in FIG. **6B**, the source electrode layer **405a** or the drain electrode layer **405b** covers the periphery of the second oxide semiconductor film **403b**, and the gate electrode layer **401b** covers a region of the second oxide semiconductor film **403b** which is not covered with the source electrode layer **405a** or the drain electrode layer **405b**. Thus, the second oxide semiconductor film **403b** is not exposed in etching of the gate electrode layer **401b**. As illustrated in FIG. **6A**, the top surface of the source electrode layer **405a** is covered with the first protective layer **410a** and the top surface of the drain electrode layer **405b** is covered with the second protective layer **410b**; thus, the source electrode layer **405a** and the drain electrode layer **405b** are not removed in etching of the gate electrode layer **401b**.

The structures of the transistors illustrated in FIG. **4E**, FIGS. **5A** to **5C**, and FIG. **6A** are partly different from one another; however, the present invention is not limited to these structures, and various combinations are possible.

Further, this embodiment can be freely combined with Embodiment 1.

It is needless to say that in this embodiment, the same reference numerals and the same materials are used for the same parts as those in Embodiment 1.

(Embodiment 3)

In this embodiment, an example of a semiconductor device including the transistors described in Embodiment 1 or 2 is described with reference to FIGS. **7A** and **7B**.

The semiconductor device illustrated in FIGS. **7A** and **7B** includes transistors **740** and **750** including a first semiconductor material in a lower portion, and a transistor **610** including a second semiconductor material in an upper portion. The transistor **610** has a structure similar to that of the transistor **441e** described in Embodiment 2. The same reference numerals are used for the same parts as those in FIGS. **6A** and **6B**. FIG. **7B** is a circuit diagram of the semiconductor device in FIG. **7A**.

Here, the first semiconductor material and the second semiconductor material are preferably materials having different band gaps. For example, the first semiconductor material may be a semiconductor material other than an oxide semiconductor (e.g., silicon) and the second semiconductor material may be an oxide semiconductor. A transistor including a material such as silicon can easily operate at high speed. On the other

hand, charge can be held in a transistor including an oxide semiconductor for a long time owing to its characteristics.

As a substrate used in the semiconductor device, a single crystal semiconductor substrate or a polycrystalline semiconductor substrate made of silicon or silicon carbide, a compound semiconductor substrate made of silicon germanium or the like, a silicon on insulator (SOI) substrate, or the like can be used. A channel formation region of the transistor can be formed in or over the semiconductor substrate. The semiconductor device in FIG. **7A** is an example in which the channel formation region is formed in the semiconductor substrate to form a lower transistor.

In the semiconductor device in FIG. **7A**, a single crystal silicon substrate is used as a substrate **700**, and the transistors **740** and **750** are formed using the single crystal silicon substrate. Single crystal silicon is used as the first semiconductor material. The transistor **740** is an n-channel transistor and the transistor **750** is a p-channel transistor. The transistor **740** and the transistor **750** which are electrically connected to each other form a complementary metal oxide semiconductor (CMOS) circuit **760**.

In this embodiment, the single crystal silicon substrate imparting p-type conductivity is used as the substrate **700**; thus, an n-well is formed by adding an impurity element imparting n-type conductivity to a region in which the p-channel transistor **750** is to be formed. A channel formation region **753** of the transistor **750** is formed in the n-well. As the impurity element imparting n-type conductivity, phosphorus (P), arsenic (As), or the like can be used.

Here, an impurity element imparting p-type conductivity is not added to a region in which the n-channel transistor **740** is to be formed; however, a p-well may be formed by adding an impurity element imparting p-type conductivity. As the impurity element imparting p-type conductivity, boron (B), aluminum (Al), gallium (Ga), or the like may be used.

Meanwhile, when a single-crystal silicon substrate imparting n-type conductivity is used, an impurity element imparting p-type conductivity may be added to form a p-well.

The transistor **740** includes a channel formation region **743**, an n-type impurity region **744** functioning as a lightly doped drain (LDD) region or an extension region, an n-type impurity region **745** functioning as a source region or a drain region, a gate insulating film **742**, and a gate electrode layer **741**. The n-type impurity region **745** has a higher impurity concentration than the n-type impurity region **744**. A side surface of the gate electrode layer **741** is provided with a sidewall insulating layer **746**. With the use of the gate electrode layer **741** and the sidewall insulating layer **746** as masks, the n-type impurity region **744** and the n-type impurity region **745** which have different impurity concentrations can be formed in a self-aligned manner.

The transistor **750** includes the channel formation region **753**, a p-type impurity region **754** functioning as a lightly doped drain (LDD) region or an extension region, a p-type impurity region **755** functioning as a source region or a drain region, a gate insulating film **752**, and a gate electrode layer **751**. The p-type impurity region **755** has a higher impurity concentration than the p-type impurity region **754**. A side surface of the gate electrode layer **751** is provided with a sidewall insulating layer **756**. With the use of the gate electrode layer **751** and the sidewall insulating layer **756** as masks, the p-type impurity region **754** and the p-type impurity region **755** which have different impurity concentrations can be formed in a self-aligned manner.

In the substrate **700**, the transistor **740** and the transistor **750** are isolated from each other by an element isolation region **789**. An insulating film **788** and an insulating film **687**

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are stacked over the transistor 740 and the transistor 750. A wiring layer 647 electrically connected to the n-type impurity region 745 through an opening in the insulating film 788 and the insulating film 687 and a wiring layer 657 electrically connected to the p-type impurity region 755 through an opening in the insulating film 788 and the insulating film 687 are provided over the insulating film 687. A wiring layer 748 is provided over the insulating film 687 so as to electrically connect the transistor 740 and the transistor 750. The wiring layer 748 is electrically connected to the n-type impurity region 745 through an opening in the insulating film 788 and the insulating film 687 and reaching the n-type impurity region 745. Further, the wiring layer 748 is electrically connected to the p-type impurity region 755 through an opening in the insulating film 788 and the insulating film 687 and reaching the p-type impurity region 755.

An insulating film 686 is provided over the insulating film 687, the wiring layer 647, the wiring layer 748, and the wiring layer 657. A wiring layer 658 is formed over the insulating film 686. The wiring layer 658 is electrically connected to a gate wiring through an opening in the insulating films 788, 687, and 686. The gate wiring is formed over the gate insulating film 742 and the channel formation region 753. The gate wiring branches into the gate electrode layer 741 and the gate electrode layer 751.

The semiconductor device of this embodiment is not limited to the structure in FIG. 7A. As the transistors 740 and 750, a transistor containing silicide or a transistor which does not include a sidewall insulating layer may be used. When a structure that contains silicide is used, resistance of the source region and the drain region can be further lowered and the speed of the semiconductor device is increased. Further, the semiconductor device can be operated at low voltage; thus, power consumption of the semiconductor device can be reduced.

Next, the structures of upper elements provided over the lower transistor in the semiconductor device in FIGS. 7A and 7B are described.

An insulating film 684 is stacked over the insulating film 686 and the wiring layer 658. The conductive layer 491 and a wiring layer 692 are formed over the insulating film 684. The insulating film 434 is provided so as to cover the conductive layer 491 and the wiring layer 692. The oxide insulating film 435 is provided over the insulating film 434. The insulating film 437 containing gallium oxide, the first oxide semiconductor film 403a, and the second oxide semiconductor film 403b having a composition different from that of the first oxide semiconductor film 403a are stacked in this order over the oxide insulating film 435. The source electrode layer 405a and the drain electrode layer 405b each including projecting portions are provided over the second oxide semiconductor film 403b. The first protective layer 410a which overlaps with and is in contact with the source electrode layer 405a and the second protective layer 410b which overlaps with and is in contact with the drain electrode layer 405b are provided. The gate insulating film 402 is provided over and in contact with a region of the second oxide semiconductor film 403b which overlaps with neither the source electrode layer 405a nor the drain electrode layer 405b (a channel formation region). The gate electrode layers 401a and 401b are provided over the gate insulating film 402.

The capacitor 690 is also formed over the insulating film 435 by the same process as that of the transistor 610. The source electrode layer 405a serves as one electrode of the capacitor 690. Capacitor electrode layers 693a and 693b serve as the other electrode of the capacitor 690. The first protective layer 410a and an insulating film 682, which is

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formed in the same step as the gate insulating film 402, which are provided between the source electrode layer 405a and the capacitor electrode layer 693a serve as dielectrics. The capacitor electrode layers 693a and 693b are formed in the same step as the gate electrode layers 401a and 401b.

By setting the potential of the conductive layer 491 to GND (or a fixed potential), the conductive layer 491 serves as a back gate which controls the electrical characteristics of the transistor 610. The conductive layer 491 has a function of preventing static electricity. In the case where the threshold voltage of the transistor 610 is not required to be controlled by the conductive layer 491 in order to make the transistor 610 be a normally-off transistor, the conductive layer 491 is not necessarily provided. In the case where the transistor 610 is used for part of a particular circuit and a problem might be caused by providing the conductive layer 491, the conductive layer 491 is not necessarily provided in the circuit.

The wiring layer 692 is electrically connected to the wiring layer 658 through an opening in the insulating film 684. In this embodiment, planarization treatment using a CMP method is performed on the insulating film 684.

The insulating film 434 is provided between the lower portion and the upper portion in the semiconductor device. The insulating film 434 functions as a barrier film for preventing impurities such as hydrogen which cause degradation or variation in electrical characteristics of the transistor 610 from entering the upper portion from the lower portion. Thus, the insulating film 434 is preferably formed using a fine organic insulating film (e.g., an aluminum oxide film or a silicon nitride film) having a high blocking property of impurities or the like.

In the case of using the same manufacturing method as that described in Embodiment 2, the transistor 610 can be manufactured similarly to the transistor 441e. The method for manufacturing the transistor 610 is briefly described.

The conductive layer 491 and the wiring layer 692 are formed over the insulating film 684 which is provided over the transistors 740 and 750.

Next, the insulating film 434 is formed so as to cover the conductive layer 491 and the wiring layer 692.

Then, an oxide insulating film having projecting portions reflecting the shapes of the conductive layer 491 and the wiring layer 692 is formed over the insulating film 434. CMP treatment is performed on the oxide insulating film, whereby the oxide insulating film over the conductive layer 491 and the wiring layer 692 is selectively removed and the surface of the oxide insulating film is planarized. Accordingly, the planarized oxide insulating film 435 is formed.

Subsequently, part of the insulating film 434 over the top surface of the wiring layer 692 is selectively removed, so that an opening for exposing the top surface of the wiring layer 692 is formed.

Next, the insulating film 437 containing gallium oxide, the first oxide semiconductor film 403a, and the second oxide semiconductor film 403b are successively formed by a sputtering method without exposure to the air, and are selectively etched with one photomask.

A gallium oxide film is used as the insulating film 437 containing gallium oxide. The first oxide semiconductor film 403a is formed to be what we call a CAAC-OS film using an oxide target having an atomic ratio of In:Ga:Zn=3:1:2 in an oxygen atmosphere (oxygen: 100%). The film includes a crystal part in which c-axes are aligned in the direction parallel to a normal vector of a surface where the film is formed or a normal vector of a surface of the film, triangular or hexagonal atomic arrangement which is seen from the direction perpendicular to the a-b plane is formed, and metal atoms

are arranged in a layered manner or metal atoms and oxygen atoms are arranged in a layered manner when seen from the direction perpendicular to the c-axis. The second oxide semiconductor film **403b** is formed to be a CAAC-OS film using an oxide target having an atomic ratio of In:Ga:Zn=1:1:1 in an oxygen atmosphere (oxygen: 100%). The sum of the thicknesses of the first oxide semiconductor film **403a** and the second oxide semiconductor film **403b** of the completed transistor is greater than or equal to 5 nm and less than or equal to 10 nm. An example in which the oxide semiconductor film includes crystal parts shortly after the oxide semiconductor film is formed is described in this embodiment; however, crystal parts may be formed by performing heat treatment after the film formation.

A conductive film is formed over the second oxide semiconductor film **403b** by a sputtering method or the like, and a silicon oxide film is formed over the conductive film. Next, a resist mask is formed over the silicon oxide film, and first etching is performed to remove the conductive film to approximately half the thickness so that the silicon oxide film partly has a small thickness. Ashing is performed on the resist mask for reducing the area of the resist mask. After that, second etching is performed with the resist mask, which is reduced in size, so that the source electrode layer **405a** and the drain electrode layer **405b** each including projecting portions are formed. The first protective layer **410a** remains over a region of the source electrode layer **405a** which has a large thickness, and the second protective layer **410b** remains over a region of the drain electrode layer **405b** which has a large thickness. The source electrode layer **405a** is electrically connected to the wiring layer **692** through the opening in the insulating film **434**.

Next, the gate insulating film **402** is formed over the second oxide semiconductor film **403b**, the first protective layer **410a**, and the second protective layer **410b**. As a material of the gate insulating film **402**, a gallium oxide film is used in this embodiment.

Next, a conductive film is formed over the gate insulating film **402** by a sputtering method, an evaporation method, or the like. The conductive film is etched so that the gate electrode layers **401a** and **401b** and the capacitor electrode layers **693a** and **693b** are formed. Next, part of the gate insulating film **402** is removed with the use of the gate electrode layers **401a** and **401b** as masks. In the same step, part of the gate insulating film **402** is removed with the use of the capacitor electrode layers **693a** and **693b** as masks, so that the insulating film **682** is formed. When part of the gate insulating film **402** which is a gallium oxide film is removed, the first protective layer **410a** and the second protective layer **410b** which are silicon oxide films function as etching stoppers, that is, protect the source electrode layer **405a** and the drain electrode layer **405b** from etching treatment.

Through the above steps, the transistor **610** and the capacitor **690** are completed. The first oxide semiconductor film **403a** is formed over and in contact with the insulating film **437** which is a gallium oxide film, and the gate insulating film **402**, which is a gallium oxide film, is formed over and in contact with the second oxide semiconductor film **403b**; thus, oxygen can be efficiently supplied to the first oxide semiconductor film **403a** and the second oxide semiconductor film **403b**. By providing the insulating film **437** and the gate insulating film **402**, which are gallium oxide films, unnecessary release of oxygen can be suppressed, and the first oxide semiconductor film **403a** can be kept in an oxygen excess state. Thus, in the transistor **610**, oxygen vacancies in the first oxide semiconductor film **403a** and at the interface between the insulating film **437** and the first oxide semiconductor film

403a can be compensated efficiently. Even in the case where the gate insulating film **402**, which is a gallium oxide film, has a small thickness such as 20 nm or smaller and the metal oxide film containing nitrogen is formed by a sputtering method in a later step, the gate insulating film **402** prevents impurities such as nitrogen from entering the second oxide semiconductor film **403b** provided below the film when or after the formation.

Next, the insulating film **407** and the interlayer insulating film **485** are formed over the transistor **610** and the capacitor **690**. A cross-sectional view at this stage corresponds to FIG. **7A**. Further, as described in Embodiment 1, a semiconductor device having a multilayer structure in which an embedded wiring is formed in the interlayer insulating film **485** and another semiconductor element, another wiring, or the like is formed above the embedded wiring may be manufactured.

Further, this embodiment can be freely combined with Embodiment 1 or 2. (Embodiment 4)

As another example of a semiconductor device including the transistors described in Embodiment 1 or 2, a cross-sectional view of a NOR circuit, which is a logic circuit, is illustrated in FIG. **8A**. FIG. **8B** is a circuit diagram of the NOR circuit in FIG. **8A**, and FIG. **8C** is a circuit diagram of a NAND circuit.

In the NOR circuit illustrated in FIGS. **8A** and **8B**, p-channel transistors **801** and **802** each have a structure similar to that of the transistor **750** in FIGS. **7A** and **7B** in that a single crystal silicon substrate is used for a channel formation region, and n-channel transistors **803** and **804** each have a structure similar to that of the transistor **610** in FIGS. **7A** and **7B** and that of the transistor **441e** in Embodiment 1 in that an oxide semiconductor film is used for a channel formation region.

In the transistors **803** and **804** in the NOR circuit illustrated in FIGS. **8A** and **8B**, the conductive layer **491** is provided so as to overlap with a gate electrode layer with an oxide semiconductor film provided therebetween in order to control the electrical characteristics of the transistors. By controlling the potential of the conductive layer to GND, for example, the threshold voltages of the transistors **803** and **804** are increased, so that the transistors can be normally off. In the NOR circuit in this embodiment, conductive layers which are provided in the transistors **803** and **804** and can function as back gates are electrically connected to each other. However, the present invention is not limited to the structure, and the conductive layers functioning as back gates may be electrically controlled independently.

In the semiconductor device illustrated in FIG. **8A**, a single crystal silicon substrate is used as a substrate **800**, the transistor **802** is formed using the single crystal silicon substrate, and the transistor **803** in which stacked oxide semiconductor films are used for a channel formation region is formed over the transistor **802**.

The gate electrode layers **401a** and **401b** of the transistor **803** are electrically connected to a wiring layer **832**. The wiring layer **832** is electrically connected to a wiring layer **835**. The gate electrode layers **401a** and **401b** of the transistor **803** are electrically connected to an embedded wiring, and the embedded wiring is electrically connected to a conductive layer **842**. Note that the embedded wiring includes the first barrier metal film **486**, the second barrier metal film **488**, and the low-resistance conductive layer **487** covered by the first barrier metal film **486** and the second barrier metal film **488**. The method for forming the embedded wiring is described in Embodiment 1. Thus, detailed description thereof is omitted here.

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The wiring layer **832** is formed in an opening in insulating films **826** and **830**, the wiring layer **835** is formed in an opening in an insulating film **833**, and the conductive layer **842** is formed in an opening in the insulating film **434**.

An electrode layer **825** of the transistor **802** is electrically connected to an electrode layer **845b** of the transistor **803** through wiring layers **831** and **834**. The wiring layer **831** is formed in an opening in the insulating film **830**, the wiring layer **834** is formed in an opening in the insulating film **833**, and the electrode layer **845b** is formed in an opening in the insulating film **434**. An electrode layer **845a** and the electrode layer **845b** function as source and drain electrode layers of the transistor **803**.

The first oxide semiconductor film **403a** is formed over and in contact with the insulating film **437** which is a gallium oxide film, and the gate insulating film **402**, which is a gallium oxide film, is formed over and in contact with the second oxide semiconductor film **403b**; thus, oxygen can be efficiently supplied to the first oxide semiconductor film **403a** and the second oxide semiconductor film **403b**. By providing the insulating film **437** and the gate insulating film **402**, which are gallium oxide films, unnecessary release of oxygen can be suppressed, and the first oxide semiconductor film **403a** can be kept in an oxygen excess state. Thus, in the transistor **803**, oxygen vacancies in the first oxide semiconductor film **403a** and at the interface between the insulating film **437** and the first oxide semiconductor film **403a** can be compensated efficiently. The transistor **804** has a structure and an effect which are similar to those of the transistor **803**.

In the NAND circuit in FIG. **8C**, p-channel transistors **811** and **814** each have a structure similar to that of the transistor **750** in FIGS. **7A** and **7B**, and n-channel transistors **812** and **813** each have a structure similar to that of the transistor **610** in FIGS. **7A** and **7B** in that an oxide semiconductor film is used for a channel formation region.

In the transistors **812** and **813** in the NAND circuit illustrated in FIG. **8C**, a conductive layer is provided so as to overlap with a gate electrode layer with an oxide semiconductor film provided therebetween in order to control the electrical characteristics of the transistors. By controlling the potential of the conductive layer to GND, for example, the threshold voltages of the transistors **812** and **813** are increased, so that the transistors can be normally off. In the NAND circuit in this embodiment, conductive layers which are provided in the transistors **812** and **813** and function as back gates are electrically connected to each other. However, the present invention is not limited to the structure, and the conductive layers functioning as back gates may be electrically controlled independently.

By applying a transistor including an oxide semiconductor for a channel formation region and having extremely small off-state current to the semiconductor device in this embodiment, power consumption of the semiconductor device can be sufficiently reduced.

A semiconductor device which is miniaturized, is highly integrated, and has stable and excellent electrical characteristics by stacking semiconductor elements including different semiconductor materials and a method for manufacturing the semiconductor device can be provided.

The NOR circuit and the NAND circuit including the transistors described in Embodiment 1 or 2 are described as examples in this embodiment; however, the present invention is not limited to the circuits, and an AND circuit, an OR circuit, or the like can be formed using the transistors described in Embodiment 1 or 2. For example, a semiconductor device (storage device) in which stored data can be held even when power is not supplied and which has an unlimited

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number of times of writing with the transistors described in Embodiment 1 or 2 can be manufactured.

FIG. **9** is an example of a circuit diagram of a semiconductor device.

In FIG. **9**, a first wiring (1st Line) is electrically connected to a source electrode layer of a transistor **160**. A second wiring (2nd Line) is electrically connected to a drain electrode layer of the transistor **160**. Any of the transistors **740**, **750**, and **802** described in this embodiment can be used as the transistor **160**.

A third wiring (3rd Line) is electrically connected to one of a source and a drain electrode layers of a transistor **162**, and a fourth wiring (4th Line) is electrically connected to a gate electrode layer of the transistor **160** and one of the source and drain electrode layers of the transistor **162** are electrically connected to one electrode of a capacitor **164**. A fifth wiring (5th Line) is electrically connected to the other electrode of the capacitor **164**.

For the transistor **162**, any of the structures of the transistors **440a**, **440b**, **440c**, **440d**, **441a**, **441b**, **441c**, **441d**, and **441e** described in Embodiment 1 or 2 can be used.

The semiconductor device having the circuit configuration in FIG. **9** utilizes a characteristic in which the potential of the gate electrode layer of the transistor **160** can be held, and thus enables data writing, holding, and reading as follows.

Writing and holding of data are described. First, the potential of the fourth wiring is set to a potential at which the transistor **162** is turned on, so that the transistor **162** is turned on. Accordingly, the potential of the third wiring is supplied to the gate electrode layer of the transistor **160** and to the capacitor **164**. That is, predetermined charge is supplied to the gate electrode layer of the transistor **160** (writing). Here, one of two kinds of charges providing different potentials (hereinafter referred to as a low-level charge and a high-level charge) is applied. After that, the potential of the fourth wiring is set to a potential at which the transistor **162** is turned off, so that the transistor **162** is turned off. Thus, the charge supplied to the gate electrode layer of the transistor **160** is held (holding).

Since the off-state current of the transistor **162** is extremely small, the charge of the gate electrode layer of the transistor **160** is held for a long time.

Next, reading of data is described. By supplying an appropriate potential (a reading potential) to the fifth wiring while supplying a predetermined potential (a constant potential) to the first wiring, the potential of the second wiring varies depending on the amount of charge held at the gate electrode layer of the transistor **160**. This is because in general, when the transistor **160** is an n-channel transistor, an apparent threshold voltage V_{th_H} in the case where the high-level potential is given to the gate electrode layer of the transistor **160** is lower than an apparent threshold voltage V_{th_L} in the case where the low-level charge is given to the gate electrode layer of the transistor **160**. Here, an apparent threshold voltage refers to the potential of the fifth wiring which is needed to turn on the transistor **160**. Thus, the potential of the fifth wiring is set to a potential V_0 between V_{th_H} and V_{th_L} , whereby charge supplied to the gate electrode layer of the transistor **160** can be determined. For example, in the case where the high-level charge is supplied in writing, when the potential of the fifth wiring is V_0 ($>V_{th_H}$), the transistor **160** is turned on. In the case where the low-level charge is supplied in writing, even when the potential of the fifth wiring is V_0 ($<V_{th_L}$), the transistor **160** remains off. Therefore, the held data can be read by measuring the potential of the second wiring.

Note that in the case where memory cells are arrayed to be used, only data of desired memory cells needs to be read. In the case where such reading is not performed, a potential at which the transistor **160** is turned off regardless of the state of the gate electrode layer of the transistor **160**, that is, a potential smaller than V_{th_H} may be given to the fifth wiring. Alternatively, a potential at which the transistor **160** is turned on regardless of the state of the gate electrode layer, that is, a potential higher than V_{th_L} may be given to the fifth line.

FIG. **10** illustrates another example of one embodiment of the structure of the storage device.

FIG. **10** is a perspective view of a memory device. The memory device illustrated in FIG. **10** includes a plurality of layers of memory cell arrays (memory cell arrays **3400(1)** to **3400(n)** (n is an integer greater than or equal to 2)) each including a plurality of memory cells as memory circuits in the upper portion, and a logic circuit **3004** in the lower portion which is necessary for operating the memory cell arrays **3400(1)** to **3400(n)**.

FIG. **10** illustrates the logic circuit **3004**, the memory cell array **3400(1)**, and the memory cell array **3400(2)**, and illustrates a memory cell **3170a** and a memory cell **3170b** as typical examples among the plurality of memory cells included in the memory cell array **3400(1)** and the memory cell array **3400(2)**. The memory cell **3170a** and the memory cell **3170b** can have a configuration similar to the circuit configuration described in this embodiment with reference to FIG. **9**, for example.

A transistor in which a channel formation region is formed in an oxide semiconductor film is used as each transistor included in the memory cells **3170a** and **3170b**. The structure of the transistor in which the channel formation region is formed in the oxide semiconductor film is the same as the structure described in Embodiment 1; thus, the description of the structure is omitted.

The logic circuit **3004** includes a transistor in which a semiconductor material other than an oxide semiconductor is used as a channel formation region. For example, the transistor can be a transistor obtained in such a manner that an element isolation insulating layer is provided on a substrate including a semiconductor material (e.g., silicon) and a region serving as the channel formation region is formed in a region surrounded by the element isolation insulating layer. Note that the transistor may be a transistor obtained in such a manner that the channel formation region is formed in a semiconductor film such as a polycrystalline silicon film formed on an insulating surface or in a silicon film of an SOI substrate.

The memory cell arrays **3400(1)** to **3400(n)** and the logic circuit **3004** are stacked with interlayer insulating layers provided therebetween, and electrical connection or the like may be established as appropriate by an electrode or a wiring penetrating the interlayer insulating layers.

When a transistor including an oxide semiconductor for a channel formation region and having extremely small off-state current is applied to the semiconductor device in this embodiment, the semiconductor device can store data for an extremely long period. In other words, power consumption can be adequately reduced because refresh operation becomes unnecessary or the frequency of refresh operation can be extremely low. Moreover, stored data can be held for a long period even when power is not supplied (note that a potential is preferably fixed).

Further, in the semiconductor device described in this embodiment, high voltage is not needed for writing data and there is no problem of deterioration of elements. For example, unlike a conventional non-volatile memory, it is not necessary

to inject and extract electrons into and from a floating gate; thus, the problem of deterioration of a gate insulating film does not occur. In other words, the semiconductor device according to one embodiment of the present invention does not have a limit on the number of times of writing which is a problem in a conventional nonvolatile memory, and reliability thereof is drastically improved. Furthermore, data is written depending on the on state and the off state of the transistor, whereby high-speed operation can be easily realized.

As described above, a miniaturized and highly-integrated semiconductor device having high electrical characteristics and a method for manufacturing the semiconductor device can be provided.

This embodiment can be freely combined with any of Embodiment 1, Embodiment 2, and Embodiment 3. (Embodiment 5)

In this embodiment, a central processing unit (CPU) at least part of which includes any of the transistors **440a**, **440b**, **440c**, **440d**, **441a**, **441b**, **441c**, **441d**, and **441e** described in Embodiment 1 or 2 is described as an example of a semiconductor device in this embodiment.

FIG. **11A** is a block diagram illustrating a specific structure of the CPU. The CPU illustrated in FIG. **11A** includes an arithmetic logic unit (ALU, an arithmetic logic circuit) **1191**, an ALU controller **1192**, an instruction decoder **1193**, an interrupt controller **1194**, a timing controller **1195**, a register **1196**, a register controller **1197**, a bus interface (Bus I/F) **1198**, a rewritable ROM **1199**, and an ROM interface (ROM I/F) **1189** over a substrate **1190**. A semiconductor substrate, an SOI substrate, a glass substrate, or the like is used as the substrate **1190**. The ROM **1199** and the ROM interface **1189** may each be provided over a separate chip. Obviously, the CPU shown in FIG. **11A** is just an example in which the configuration has been simplified, and an actual CPU may have various configurations depending on the application.

An instruction that is input to the CPU through the bus interface **1198** is input to the instruction decoder **1193** and decoded therein, and then, input to the ALU controller **1192**, the interrupt controller **1194**, the register controller **1197**, and the timing controller **1195**.

The ALU controller **1192**, the interrupt controller **1194**, the register controller **1197**, and the timing controller **1195** conduct various controls in accordance with the decoded instruction. Specifically, the ALU controller **1192** generates signals for controlling the operation of the ALU **1191**. While the CPU is executing a program, the interrupt controller **1194** judges an interrupt request from an external input/output device or a peripheral circuit on the basis of its priority or a mask state, and processes the request. The register controller **1197** generates an address of the register **1196**, and reads/writes data from/to the register **1196** in accordance with the state of the CPU.

The timing controller **1195** generates signals for controlling operation timings of the ALU **1191**, the ALU controller **1192**, the instruction decoder **1193**, the interrupt controller **1194**, and the register controller **1197**. For example, the timing controller **1195** includes an internal clock generator for generating an internal clock signal CLK2 based on a reference clock signal CLK1, and supplies the internal clock signal CLK2 to the above circuits.

In the CPU illustrated in FIG. **11A**, a memory cell is provided in the register **1196**. As the memory cell of the register **1196**, the memory cell described in Embodiment 4 can be used.

In the CPU illustrated in FIG. **11A**, the register controller **1197** selects an operation of holding data in the register **1196** in accordance with an instruction from the ALU **1191**. That is,

the register controller **1197** selects whether data is held by a flip-flop or a capacitor in the memory cell included in the register **1196**. When data holding by the flip-flop is selected, power supply voltage is supplied to the memory cell in the register **1196**. When data holding by the capacitor is selected, the data is rewritten in the capacitor, and supply of power supply voltage to the memory cell in the register **1196** can be stopped.

The power supply can be stopped by providing a switching element between a memory cell group and a node to which a power supply potential VDD or a power supply potential VSS is supplied, as illustrated in FIG. **11B** or FIG. **11C**. Circuits illustrated in FIGS. **11B** and **11C** are described below.

FIGS. **11B** and **11C** each illustrate an example of a structure of a memory circuit in which any of the transistors **440a**, **440b**, **440c**, **440d**, **441a**, **441b**, **441c**, **441d**, and **441e** described in Embodiment 1 or 2 is used as a switching element for controlling supply of a power supply potential to a memory cell.

The memory device illustrated in FIG. **11B** includes a switching element **1141** and a memory cell group **1143** including a plurality of memory cells **1142**. Specifically, as each of the memory cells **1142**, the memory cell described in Embodiment 3 can be used. Each of the memory cells **1142** included in the memory cell group **1143** is supplied with the high-level power supply potential VDD via the switching element **1141**. Further, each of the memory cells **1142** included in the memory cell group **1143** is supplied with a potential of a signal IN and the low-level power supply potential VSS.

In FIG. **11B**, any of the transistors **440a**, **440b**, **440c**, **440d**, **441a**, **441b**, **441c**, **441d**, and **441e** described in Embodiment 1 or 2 is used as the switching element **1141**, and the switching of the transistor is controlled by a signal Sig A supplied to a gate electrode layer thereof.

Note that FIG. **11B** illustrates the structure in which the switching element **1141** includes only one transistor; however, without particular limitation thereon, the switching element **1141** may include a plurality of transistors. In the case where the switching element **1141** includes a plurality of transistors which serves as switching elements, the plurality of transistors may be connected to each other in parallel, in series, or in combination of parallel connection and series connection.

Although the switching element **1141** controls the supply of the high-level power supply potential VDD to each of the memory cells **1142** included in the memory cell group **1143** in FIG. **11B**, the switching element **1141** may control the supply of the low-level power supply potential VSS.

In FIG. **11C**, an example of a memory device in which each of the memory cells **1142** included in the memory cell group **1143** is supplied with the low-level power supply potential VSS via the switching element **1141** is illustrated. The supply of the low-level power supply potential VSS to each of the memory cells **1142** included in the memory cell group **1143** can be controlled by the switching element **1141**.

When a switching element is provided between a memory cell group and a node to which the power supply potential VDD or the power supply potential VSS is supplied, data can be held even in the case where an operation of a CPU is temporarily stopped and the supply of the power supply voltage is stopped; accordingly, power consumption can be reduced. Specifically, for example, while a user of a personal computer does not input data to an input device such as a keyboard, the operation of the CPU can be stopped, so that the power consumption can be reduced.

Although the CPU is given as an example, the transistor can also be applied to an LSI such as a digital signal processor (DSP), a custom LSI, or a field programmable gate array (FPGA).

The structures, methods, and the like which are described in this embodiment can be combined as appropriate with any of the structures, methods, and the like which are described in the other embodiments.

(Embodiment 6)

A semiconductor device disclosed in this specification can be applied to a variety of electronic devices (including game machines). Examples of the electronic devices include display devices of televisions, monitors, and the like, lighting devices, desktop personal computers and laptop personal computers, word processors, image reproduction devices which reproduce still images or moving images stored in recording media such as digital versatile discs (DVDs), portable compact disc (CD) players, radio receivers, tape recorders, headphone stereos, stereos, cordless phone handsets, transceivers, portable wireless devices, mobile phones, car phones, portable game machines, calculators, portable information terminals, electronic notebooks, e-book readers, electronic translators, audio input devices, cameras such as still cameras and video cameras, electric shavers, high-frequency heating appliances such as microwave ovens, electric rice cookers, electric washing machines, electric vacuum cleaners, air-conditioning systems such as air conditioners, dishwashers, dish dryers, clothes dryers, futon dryers, electric refrigerators, electric freezers, electric refrigerator-freezers, freezers for preserving DNA, smoke detectors, radiation counters, and medical equipment such as dialyzers. Further, the examples include industrial equipment such as guide lights, traffic lights, belt conveyors, elevators, escalators, industrial robots, and power storage systems. In addition, oil engines, moving objects driven by electric motors using power from the non-aqueous secondary batteries, and the like are also included in the category of electronic devices. Examples of the moving objects include electric vehicles (EV), hybrid electric vehicles (HEV) which include both an internal-combustion engine and a motor, plug-in hybrid electric vehicles (PHEV), tracked vehicles in which caterpillar tracks are substituted for wheels of these vehicles, motorized bicycles including motor-assisted bicycles, motorcycles, electric wheelchairs, golf carts, boats, ships, submarines, helicopters, aircrafts, rockets, artificial satellites, space probes, planetary probes, spacecrafts, and the like. Specific examples of these electronic devices are illustrated in FIGS. **12A** to **12C** and FIGS. **13A** to **13C**.

FIGS. **12A** and **12B** illustrate a tablet terminal that can be folded in two. FIG. **12A** illustrates the tablet terminal which is open. The tablet terminal includes a housing **9630**, a display portion **9631a**, a display portion **9631b**, a switch **9034** for switching display modes, a power switch **9035**, a switch **9036** for switching to power-saving mode, a fastener **9033**, and an operation switch **9038**.

In such a portable device illustrated in FIGS. **12A** and **12B**, an SRAM or a DRAM is used as a memory element for temporarily storing image data. For example, the semiconductor device described in Embodiment 4 can be used as a memory. The semiconductor device described in the above embodiment employed for the memory element enables writing and reading of data to be performed at high speed, enables data to be retained for a long time, and enables power consumption to be sufficiently reduced. A CPU for performing image processing or arithmetic processing is used in the portable device illustrated in FIGS. **12A** and **12B**. As the CPU, the CPU described in Embodiment 5 can be used, in which

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case the CPU described in Embodiment 5 is used, power consumption of the portable device can be reduced.

Part of the display portion **9631a** can be a touch panel region **9632a**, and data can be input by touching operation keys **9638** that are displayed. Note that FIG. 12A shows, as an example, that half of the area of the display portion **9631a** has only a display function and the other half of the area has a touch panel function. However, the structure of the display portion **9631a** is not limited to this, and all the area of the display portion **9631a** may have a touch panel function. For example, all the area of the display portion **9631a** can display keyboard buttons and serve as a touch panel while the display portion **9631b** can be used as a display screen.

Like the display portion **9631a**, part of the display portion **9631b** can be a touch panel region **9632b**. When a finger, a stylus, or the like touches the place where a button **9639** for switching to keyboard display is displayed in the touch panel, keyboard buttons can be displayed on the display portion **9631b**.

Touch input can be performed concurrently on the touch panel regions **9632a** and **9632b**.

The switch **9034** for switching display modes can switch display orientation (e.g., between landscape mode and portrait mode) and select a display mode (switch between monochrome display and color display), for example. With the switch **9036** for switching to power-saving mode, the luminance of display can be optimized in accordance with the amount of external light at the time when the tablet terminal is in use, which is detected with an optical sensor incorporated in the tablet terminal. The tablet terminal may include another detection device such as a sensor for detecting orientation (e.g., a gyroscope or an acceleration sensor) in addition to the optical sensor.

Although FIG. 12A shows the example where the display area of the display portion **9631a** is the same as that of the display portion **9631b**, there is no particular limitation on the display portions **9631a** and **9631b**. They may differ in size and/or image quality. For example, one of them may be a display panel that can display higher-definition images than the other.

FIG. 12B illustrates the tablet terminal which is closed. The tablet terminal includes the housing **9630**, a solar battery **9633**, a charge/discharge control circuit **9634**, a battery **9635**, and a DC to DC converter **9636**. As an example, FIG. 12B illustrates the charge/discharge control circuit **9634** including the battery **9635** and the DC to DC converter **9636**.

Since the tablet terminal can be folded in two, the housing **9630** can be closed when the tablet terminal is not in use. Thus, the display portions **9631a** and **9631b** can be protected, thereby providing a tablet terminal with high endurance and high reliability for long-term use.

The tablet terminal illustrated in FIGS. 12A and 12B can also have a function of displaying various kinds of data (e.g., a still image, a moving image, and a text image), a function of displaying a calendar, a date, the time, or the like on the display portion, a touch-input function of operating or editing data displayed on the display portion by touch input, a function of controlling processing by various kinds of software (programs), and the like.

Power can be supplied to a touch panel, a display portion, an image signal processor, or the like by the solar battery **9633** attached on a surface of the tablet terminal. Note that the solar battery **9633** can be provided on one or both surfaces of the housing **9630**, so that the battery **9635** can be charged efficiently. The use of a lithium ion battery as the battery **9635** brings an advantage such as reduction in size.

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The structure and operation of the charge/discharge control circuit **9634** illustrated in FIG. 12B are described with reference to a block diagram in FIG. 12C. FIG. 12C illustrates the solar battery **9633**, the battery **9635**, the DC to DC converter **9636**, a converter **9637**, switches SW1 to SW3, and the display portion **9631**. The battery **9635**, the DC to DC converter **9636**, the converter **9637**, and the switches SW1 to SW3 correspond to the charge/discharge control circuit **9634** illustrated in FIG. 12B.

An example of the operation performed when power is generated by the solar battery **9633** using external light is described. The voltage of power generated by the solar battery is raised or lowered by the DC to DC converter **9636** so as to be a voltage for charging the battery **9635**. Then, when power from the solar battery **9633** is used for the operation of the display portion **9631**, the switch SW1 is turned on and the voltage of the power is raised or lowered by the converter **9637** so as to be a voltage needed for the display portion **9631**. When images are not displayed on the display portion **9631**, the switch SW1 is turned off and the switch SW2 is turned on so that the battery **9635** is charged.

Here, the solar battery **9633** is shown as an example of a power generation means; however, there is no particular limitation on a way of charging the battery **9635**, and the battery **9635** may be charged with another power generation means such as a piezoelectric element or a thermoelectric conversion element (Peltier element). For example, the battery **9635** may be charged with a non-contact power transmission module that transmits and receives power wirelessly (without contact) to charge the battery or with a combination of other charging means.

In a television set **8000** in FIG. 13A, a display portion **8002** is incorporated in a housing **8001**. The display portion **8002** displays an image and a speaker portion **8003** can output sound.

A semiconductor display device such as a liquid crystal display device, a light-emitting device in which a light-emitting element such as an organic EL element is provided in each pixel, an electrophoresis display device, a digital micro-mirror device (DMD), or a plasma display panel (PDP) can be used for the display portion **8002**.

The television set **8000** may be provided with a receiver, a modem, and the like. A general television broadcast can be received with the receiver in television set **8000**. Furthermore, when the television set **8000** is connected to a communication network by wired or wireless connection via the modem, one-way (from a transmitter to a receiver) or two-way (between a transmitter and a receiver, between receivers, or the like) data communication can be performed.

In addition, the television set **8000** may include a CPU for performing information communication or a memory. The memory described in Embodiment 4 or the CPU described in Embodiment 5 can be used in the television set **8000**.

In FIG. 13A, an air conditioner which includes an indoor unit **8200** and an outdoor unit **8204** is an example of an electric device in which the CPU of Embodiment 5 is used. Specifically, the indoor unit **8200** includes a housing **8201**, an air outlet **8202**, a CPU **8203**, and the like. Although the CPU **8203** is provided in the indoor unit **8200** in FIG. 13A, the CPU **8203** may be provided in the outdoor unit **8204**. Alternatively, the CPU **8203** may be provided in both the indoor unit **8200** and the outdoor unit **8204**. By using the CPU described in Embodiment 5 as the CPU in the air conditioner, power consumption can be reduced.

In FIG. 13A, an electric refrigerator-freezer **8300** is an example of an electric device which is provided with the CPU formed using an oxide semiconductor. Specifically, the elec-

tric refrigerator-freezer **8300** includes a housing **8301**, a door for a refrigerator **8302**, a door for a freezer **8303**, a CPU **8304**, and the like. The CPU **8304** is provided in the housing **8301** in FIG. 13A. When the CPU described in Embodiment 5 is used as the CPU **8304** of the electric refrigerator-freezer **8300**, power consumption of the electric refrigerator-freezer **8300** can be reduced.

FIG. 13B illustrates an example of an electric vehicle. An electric vehicle **9700** is equipped with a secondary battery **9701**. The output of the electric power of the secondary battery **9701** is adjusted by a control circuit **9702** so that the electric power is supplied to a driving device **9703**. The control circuit **9702** is controlled by a processing unit **9704** including a ROM, a RAM, a CPU, or the like which is not illustrated. By using the CPU described in Embodiment 5 as the CPU in the electric vehicle **9700**, power consumption can be reduced.

The driving device **9703** includes a DC motor or an AC motor either alone or in combination with an internal-combustion engine. The processing unit **9704** outputs a control signal to the control circuit **9702** based on input data such as data of operation (e.g., acceleration, deceleration, or stop) by a driver or data during driving (e.g., data on an upgrade or a downgrade, or data on a load on a driving wheel) of the electric vehicle **9700**. The control circuit **9702** adjusts the electric energy supplied from the secondary battery **9701** in accordance with the control signal of the processing unit **9704** to control the output of the driving device **9703**. In the case where the AC motor is mounted, although not illustrated, an inverter which converts direct current into alternate current is also incorporated.

This embodiment can be implemented combining with another embodiment as appropriate. (Embodiment 7)

In Embodiments 3 and 4, the example in which the insulating film **434** is provided over the conductive layer **491** and openings for exposing the top surfaces of the wiring layers **692**, **834**, and **835** are provided is described. In this embodiment, an example in which the top surfaces of the wiring layers **834** and **835** are exposed by planarization treatment such as CMP in order to reduce the number of steps is illustrated in FIG. 14.

In this embodiment, the same reference numerals are used for the same parts as those in Embodiment 4.

In the semiconductor device illustrated in FIG. 14, a single crystal silicon substrate is used as the substrate **800**, the transistor **802** is formed using the single crystal silicon substrate, a transistor **815** in which stacked oxide semiconductor films are used for a channel formation region is formed over the transistor **802**.

A gate electrode layer **401** of the transistor **815** is electrically connected to the wiring layer **832**. The wiring layer **832** is electrically connected to the wiring layer **835**. The gate electrode layer **401** of the transistor **815** is electrically connected to the embedded wiring, and the embedded wiring is electrically connected to the conductive layer **842**. Note that the embedded wiring includes the first barrier metal film **486**, the second barrier metal film **488**, and the low-resistance conductive layer **487** surrounded by the first barrier metal film **486** and the second barrier metal film **488**.

The wiring layer **832** is formed over the insulating films **826** and **830**, and the wiring layer **835** is formed in an opening in the insulating film **833**.

The electrode layer **825** of the transistor **802** is electrically connected to the electrode layer **845b** of the transistor **803** through the wiring layers **831** and **834**. The wiring layer **831** is formed in an opening in the insulating film **830**, and the

wiring layer **834** is formed in an opening in the insulating film **833** and electrically connected to the wiring layer **831**. The wiring layers **834** and **835**, a wiring layer **836**, and the conductive layer **491** are formed over the insulating film **833**, and the oxide insulating film **435** is formed. After that, the oxide insulating film **435** is planarized by CMP treatment, so that the top surfaces of the wiring layers **834**, **835**, and **836** and the conductive layer **491** are exposed.

After the planarization, the insulating film **437** and the oxide semiconductor film **403** are formed and selectively etched by patterning with the use of one mask. The oxide semiconductor film **403** may be stacked oxide semiconductor films having different compositions.

After the insulating film **437** and the oxide semiconductor film **403** are formed, a conductive film is formed. This conductive film is selectively etched, so that the electrode layers **845a** and **845b** and the conductive layer **842** are formed. By performing etching plural times at this time, electrodes each including projecting portions when seen in cross-section are formed. The electrode layers **845a** and **845b** each including projecting portions function as source and drain electrode layers of the transistor **815**. The electrode layer **845a** is provided over and in contact with the wiring layer **836**. The electrode layer **845b** is provided over and in contact with the wiring layer **834**. The conductive layer **842** is provided over and in contact with the wiring layer **835**.

The gate insulating film **402**, which is a gallium oxide film, is provided over the electrode layers **845a** and **845b** and the conductive layer **842**, and is over and in contact with the oxide semiconductor film **403**. The gate electrode layer **401** is provided over the oxide semiconductor film **403** with the gate insulating film provided therebetween. The insulating film **407** functioning as a barrier film is provided so as to cover the gate electrode layer **401**.

The transistor **815** can be used instead of the transistor **803** in FIGS. 8A and 8B so that the NOR circuit in FIG. 8B can be formed.

The number of steps for manufacturing the transistor **815** is smaller than that of the transistor **803**; thus, manufacturing cost can be reduced.

This embodiment can be freely combined with any of the other embodiments.

EXAMPLE 1

In this example, STEM images of the shapes of end portions of a top-gate transistor in FIG. 15A were observed in the middle of a process for manufacturing the transistor.

The top-gate transistor in FIG. 15A includes the oxide insulating film **435** over the substrate **400** which is formed of quartz glass, the first oxide semiconductor film **403a**, the second oxide semiconductor film **403b**, the gate insulating film **402** over the second oxide semiconductor film **403b**, the gate electrode layer **401** overlapping with the second oxide semiconductor film **403b** with the gate insulating film **402** positioned therebetween, and the insulating film **407** covering the gate electrode layer **401**.

As the first oxide semiconductor film **403a**, a 5-nm-thick In—Ga—Zn-based oxide film formed with a target having an atomic ratio of In:Ga:Zn=3:1:2 was used. As the second oxide semiconductor film **403b**, a 10-nm-thick In—Ga—Zn-based oxide film formed with a target having an atomic ratio of In:Ga:Zn=1:1:1 was used.

After the second oxide semiconductor film **403b** was formed, a 100-nm-thick conductive film which was a single tungsten layer was formed. This conductive film was selectively etched, so that the electrode layers **845a** and **845b** were

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formed. By performing this etching, electrodes each including projecting portions when seen in cross-section were formed.

The conductive film was etched by dry etching using an inductively coupled plasma (ICP) etching method.

First etching conditions were as follows: an etching gas of Cl_2 , CF_4 , and O_2 ($\text{Cl}_2:\text{CF}_4:\text{O}_2=45\text{ sccm}:45\text{ sccm}:55\text{ sccm}$), a power of a power supply of 3000 W, a bias power of 110 W, and a pressure of 0.67 Pa. Second etching conditions were as follows: an etching gas of O_2 ($\text{O}_2=100\text{ sccm}$), a power of the power supply of 2000 W, a bias power of 0 W, and a pressure of 3 Pa. Third etching conditions were as follows: an etching gas of Cl_2 , CF_4 , and O_2 ($\text{Cl}_2:\text{CF}_4:\text{O}_2=45\text{ sccm}:45\text{ sccm}:55\text{ sccm}$), a power of the power supply of 3000 W, a bias power of 110 W, and a pressure of 0.67 Pa. The substrate temperature in etching was 40° C. in all the conditions.

A 20-nm-thick silicon oxynitride film was formed by a plasma CVD method as the gate insulating film 402. A cross-sectional view at this stage is shown in FIG. 15B.

FIG. 15C shows a cross-sectional STEM image of a region surrounded by dotted lines in FIG. 15B. As shown in FIG. 15C, a first taper angle $\theta 1$ was approximately 58° and a second taper angle $\theta 2$ was approximately 70°. The first taper angle $\theta 1$ is an angle formed by a planar surface of the substrate 400 and a first side surface of an end portion of the electrode layer 845b as illustrated in FIG. 15B. The second taper angle $\theta 2$ is an angle formed by the planar surface of the substrate 400 and a second side surface of the end portion of the electrode layer 845b as illustrated in FIG. 15B.

Then, etching conditions were changed from the above-described etching conditions (i.e., the etching conditions were changed twice) to the following etching conditions. First etching conditions were as follows: an etching gas of Cl_2 , CF_4 , and O_2 ($\text{Cl}_2:\text{CF}_4:\text{O}_2=45\text{ sccm}:45\text{ sccm}:55\text{ sccm}$), a power of a power supply of 3000 W, a bias power of 110 W, and a pressure of 0.67 Pa. Second etching conditions were as follows: an etching gas of O_2 ($\text{O}_2=100\text{ sccm}$), a power of the power supply of 2000 W, a bias power of 0 W, and a pressure of 3 Pa. Third etching conditions were as follows: an etching gas of Cl_2 , CF_4 , and O_2 ($\text{Cl}_2:\text{CF}_4:\text{O}_2=45\text{ sccm}:45\text{ sccm}:55\text{ sccm}$), a power of the power supply of 3000 W, a bias power of 110 W, and a pressure of 0.67 Pa. Fourth etching conditions were as follows: an etching gas of O_2 ($\text{O}_2=100\text{ sccm}$), a power of the power supply of 2000 W, a bias power of 0 W, and a pressure of 3 Pa. Fifth etching conditions were as follows: an etching gas of Cl_2 , CF_4 , and O_2 ($\text{Cl}_2:\text{CF}_4:\text{O}_2=45\text{ sccm}:45\text{ sccm}:55\text{ sccm}$), a power of the power supply of 3000 W, a bias power of 110 W, and a pressure of 0.67 Pa. The substrate temperature in etching was 40° C. in all of the conditions.

After the etching in which etching conditions were changed four times, as shown in FIG. 16A, the first taper angle $\theta 1$ of an end portion of the electrode layer 845b was approximately 30° and the second taper angle $\theta 2$ of the end portion of the electrode layer 845b was approximately 60°. An end portion of the electrode layer 845a shown in FIG. 16B had a similar shape.

By adjusting etching conditions as appropriate in such a manner, the first taper angle $\theta 1$ and the second taper angle $\theta 2$ can be adjusted. The first taper angle $\theta 1$ is preferably 20° or greater and 70° or smaller, further preferably 25° or greater and 45° or smaller. In the case where the gate insulating film 402 has a small thickness of 20 nm, the first taper angle $\theta 1$ is preferably made 25° or greater and 45° or smaller, in which case coverage is improved.

This embodiment can be freely combined with any of the other embodiments.

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This application is based on Japanese Patent Application serial No. 2012-096952 filed with Japan Patent Office on Apr. 20, 2012 and Japanese Patent Application serial No. 2012-118815 filed with Japan Patent Office on May 24, 2012, the entire contents of which are hereby incorporated by reference.

What is claimed is:

1. A semiconductor device comprising:

a first conductive layer;

a first insulating film over the first conductive layer;

an oxide semiconductor film which is over the first insulating film and comprises a channel formation region;

a source electrode layer which is over the oxide semiconductor film and is electrically connected to the oxide semiconductor film;

a drain electrode layer which is over the oxide semiconductor film and is electrically connected to the oxide semiconductor film;

a second insulating film over the oxide semiconductor film, the source electrode layer, and the drain electrode layer; and

a second conductive layer which is over the second insulating film and overlaps with the channel formation region,

wherein each of the source electrode layer and the drain electrode layer comprises a single-layer metal film, wherein the single-layer metal film comprises a first region and a second region,

wherein the first region overlaps with the oxide semiconductor film and the first conductive layer, and the second region does not overlap with the oxide semiconductor film and the first conductive layer, the first region comprising a first portion and a second portion,

wherein the second portion projects from the first portion along a channel length direction and is closer to a center of the first conductive layer than the first portion, and wherein each of the first portion and the second portion has a top flat surface substantially parallel to a bottom flat surface, both surfaces extending in the channel length direction, wherein a distance between the top flat surface and the bottom flat surface measures a thickness and the thickness of the second portion is smaller than that of the first portion.

2. The semiconductor device according to claim 1, wherein the first insulating film comprises an oxygen-excess region, and

wherein the first insulating film has a smaller thickness in a region overlapping with the first conductive layer than in another region.

3. The semiconductor device according to claim 1, wherein the oxide semiconductor film is stacked oxide semiconductor films having different compositions.

4. The semiconductor device according to claim 1, wherein the oxide semiconductor film comprises a depressed portion and overlaps with the first conductive layer, and

wherein a region having a small thickness of the oxide semiconductor film is the channel formation region.

5. The semiconductor device according to claim 1, wherein a channel length is a distance between the second portion of the source electrode layer extending in the channel length direction and the second portion of the drain electrode layer extending in the channel length direction.

6. The semiconductor device according to claim 1, further comprising:

a third insulating film overlapping with the source electrode layer and the drain electrode layer,

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wherein the second insulating film is over and in contact with the first insulating film.

7. A semiconductor device comprising:

a first conductive layer;

a first insulating film over the first conductive layer;

a second insulating film containing gallium oxide over the first insulating film;

an oxide semiconductor film which is over and in contact with the second insulating film and comprises a channel formation region;

a source electrode layer which is over the oxide semiconductor film and is electrically connected to the oxide semiconductor film;

a drain electrode layer which is over the oxide semiconductor film and is electrically connected to the oxide semiconductor film;

a third insulating film containing gallium oxide over the oxide semiconductor film, the source electrode layer, and the drain electrode layer;

a second conductive layer which is over the third insulating film and overlaps with the channel formation region,

wherein each of the source electrode layer and the drain electrode layer comprises a single-layer metal film,

wherein the single-layer metal film comprises a first region and a second region,

wherein the first region overlaps with the oxide semiconductor film overlap with the first conductive layer, and the second region does not overlap with the oxide semiconductor film and the first conductive layer, the first region comprising a first portion and a second portion,

wherein the second portion projects from the first portion along a channel length direction and is closer to a center of the first conductive layer than the first portion, and

wherein each of the first portion and the second portion has a top flat surface substantially parallel to a bottom flat surface, both surfaces extending in the channel length direction, wherein a distance between the top flat surface and the bottom flat surface measures a thickness and the thickness of the second portion is smaller than that of the first portion.

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8. The semiconductor device according to claim 7, wherein the oxide semiconductor film has a crystal structure, and

wherein the second insulating film and the third insulating film have a lower crystallinity than the oxide semiconductor film.

9. The semiconductor device according to claim 7, wherein an end portion of the second insulating film is continuously changed to an end of the oxide semiconductor film.

10. The semiconductor device according to claim 7, wherein the oxide semiconductor film is stacked oxide semiconductor films having different compositions.

11. The semiconductor device according to claim 7, wherein the oxide semiconductor film comprises a depressed portion and overlaps with the first conductive layer, and

wherein a region having a small thickness of the oxide semiconductor film is the channel formation region.

12. The semiconductor device according to claim 7, wherein a channel length is a distance between the second portion of the source electrode layer extending in the channel length direction and the second portion of the drain electrode layer extending in the channel length direction.

13. The semiconductor device according to claim 7, further comprising:

a fourth insulating film overlapping with the source electrode layer and the drain electrode layer,

wherein the third insulating film is over and in contact with the first insulating film.

14. The semiconductor device according to claim 7, further comprising:

a fourth insulating film is over and in contact with the top surface of the second portion.

15. The semiconductor device according to claim 1, further comprising:

a third insulating film is over and in contact with the top surface of the second portion.

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